Materials Characterization with Delta-L to 67 GHz

James Drewniak

Clear Signal Solutions, Inc.

james.drewniak@clearsig.com

Clear Signal Solutions

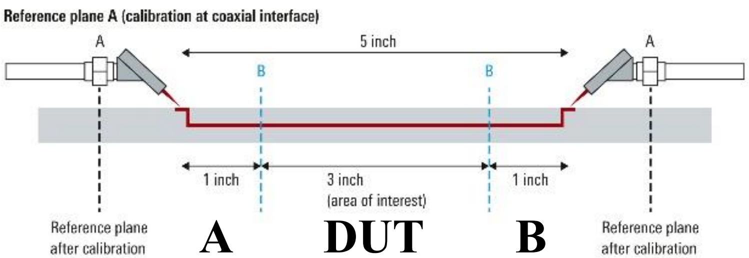
WE MAKE YOUR SIGNAL CLEAR

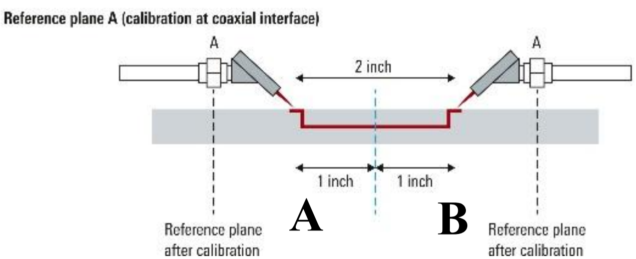
Contributors

- Xiaoning Ye – Intel
- Greg Vaught – Rohde & Schwarz
- Richard Zai – PacketMicro

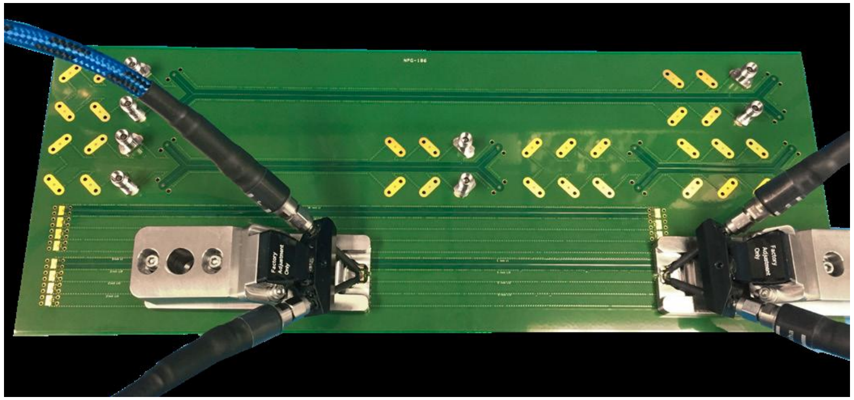
Delta-L 4.0 Methodology – to 40 GHz

2”, 5”, 10” trace lengths used for IL extraction

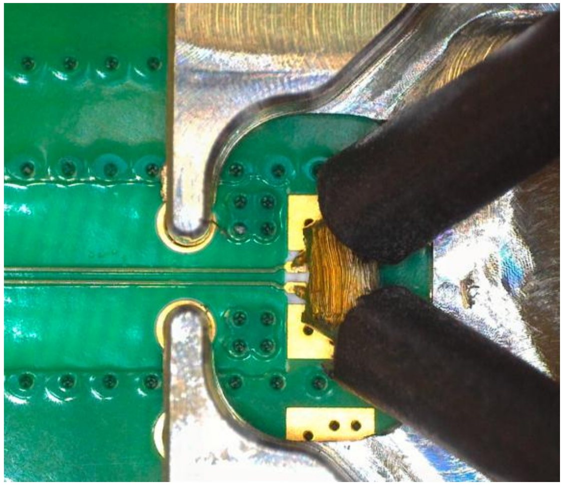




Test Vehicle with PacketMicro Probes and Bases



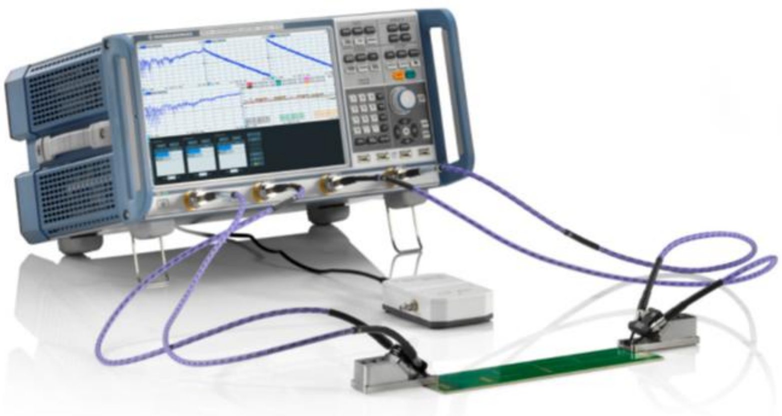
Universal Probe Launch with PacketMicro Probes



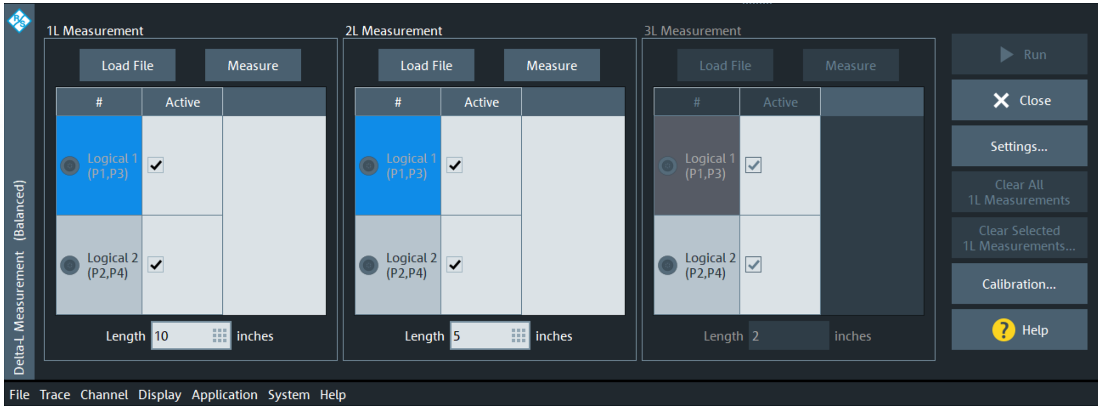
Use eigenvalue extraction method to get $\gamma=\alpha+j\beta$ for DUT, and IL in dB/inch

Workflow Implemented in Commercial Toolsets

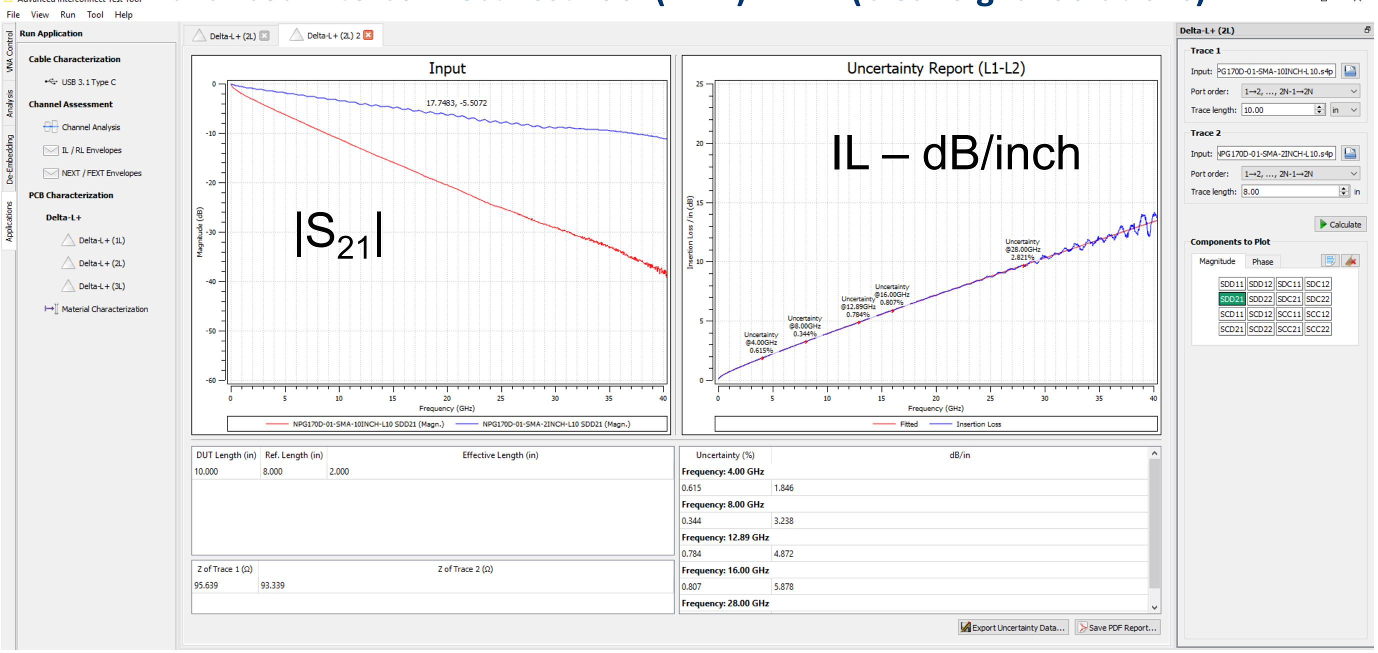
R&S®ZNB40 setup with Delta-L 4.0 probes



Delta-L Workflow for 2L on R&S®ZNB40



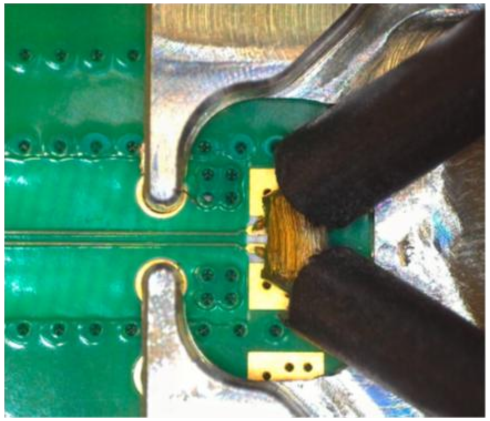
Advanced Interconnect Test Tool (AITT) – DLP (Clear Signal Solutions)

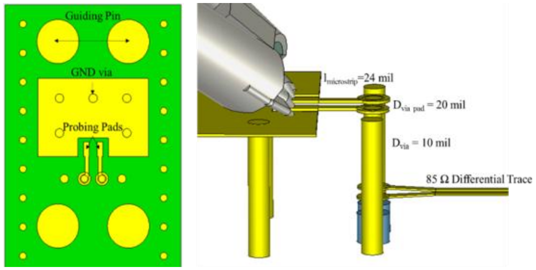


Next Step – Delta-L to 67 GHz

- Want to achieve 56 GHz over 1 lane for 224 Gbps data rate/PAM4
- Need to achieve 67 GHz for Delta-L method
  - using hand-held probes for use in large-volume measurements and in fabrication environment
  - Must have a universal footprint to accommodate handheld probes and rapid alignment/placement
  - 0.4 mm most likely a minimum probe pitch for rapid alignment due to manufacturing tolerance in PCB fab
- Must consider deviating from the legacy 2”, 5”, 10” patterns for Delta-L, e.g., 1”, 6” to meet IEEE 370 STD for de-embedding accuracy

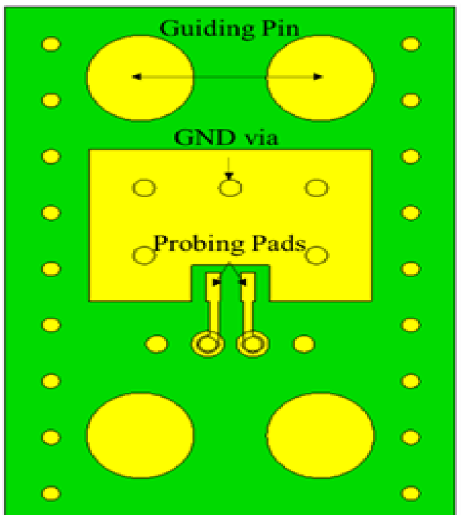
Universal Probe Launch with PacketMicro Probes

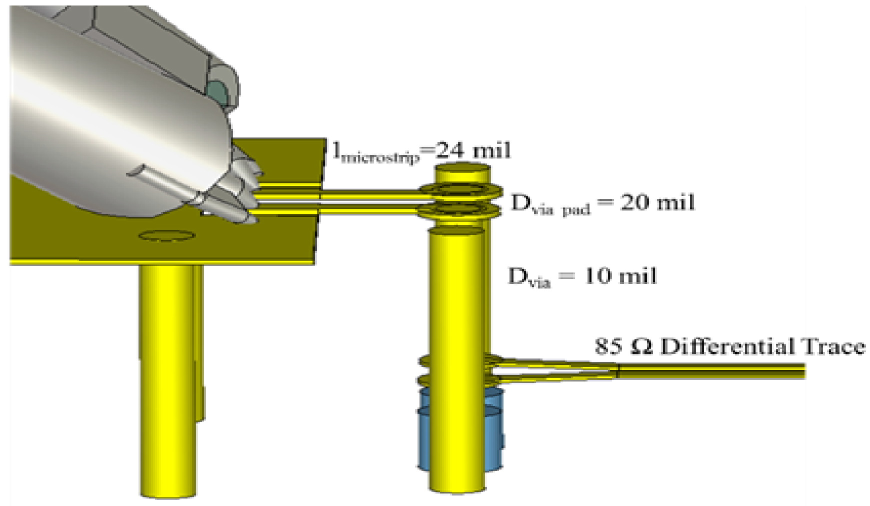


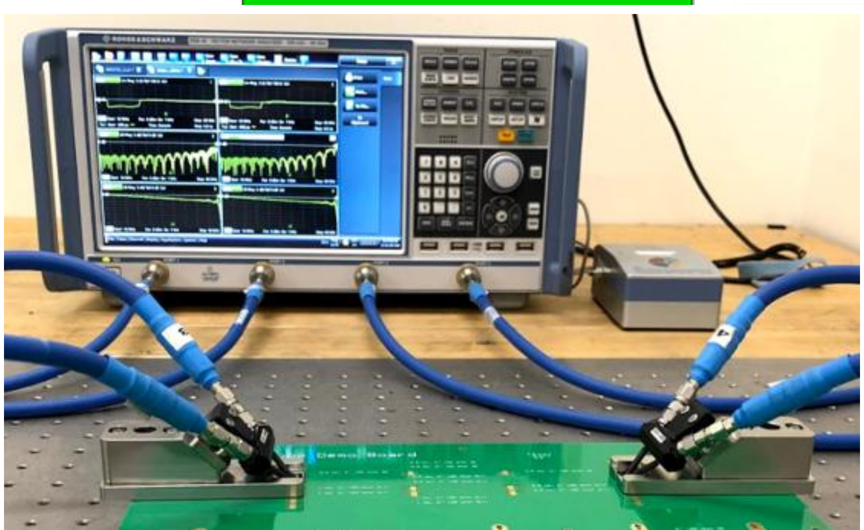


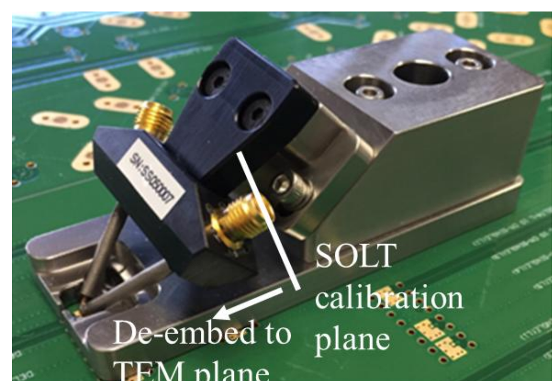
Probing Solution to 67 GHz

- Optimize probe and via transition simultaneously to achieve a RL>6dB at 67 GHZ
- Achieve an IL < 6 dB at 67 GHz by using shorter 2X Thru





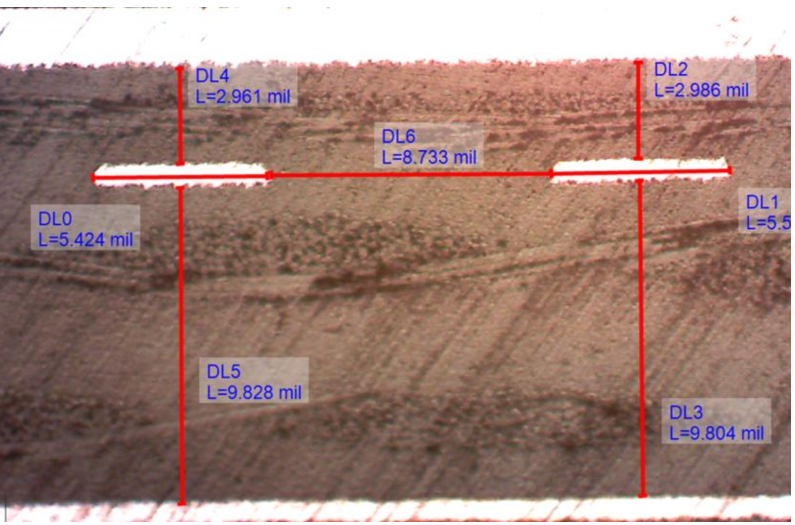


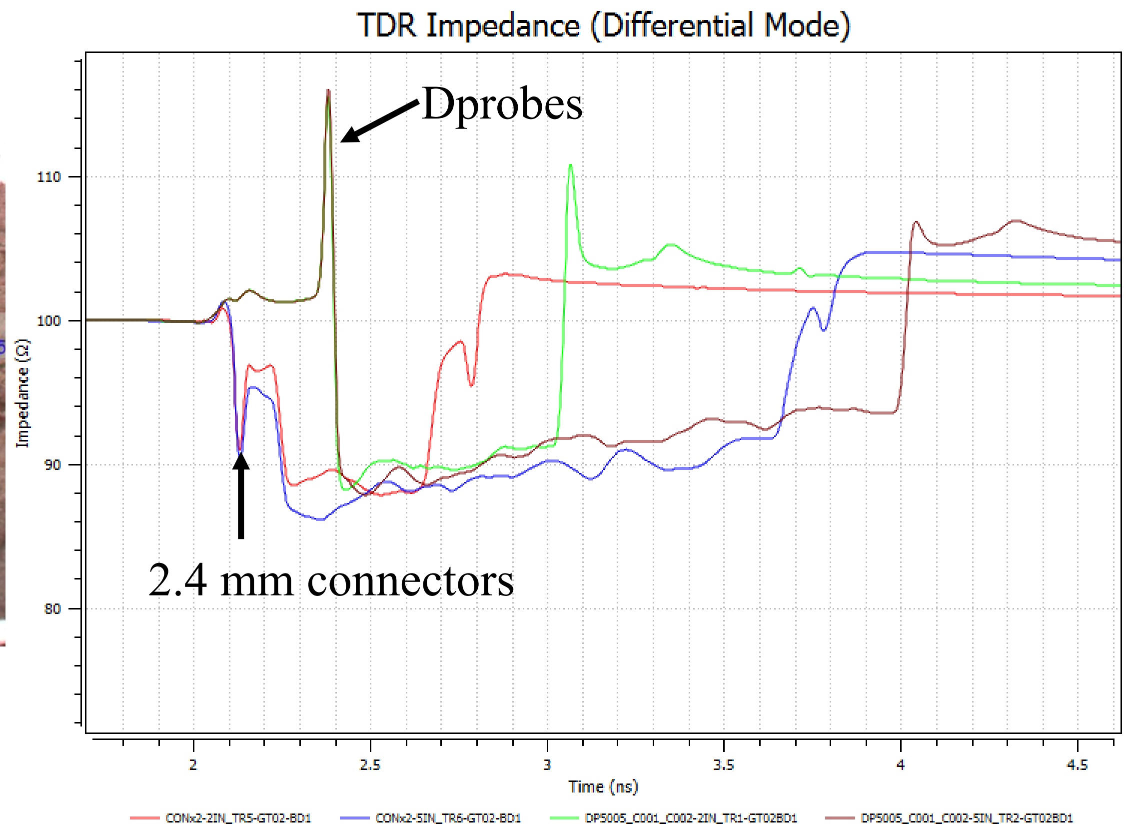


PacketMicro D-probe

Status – PCB and TDR

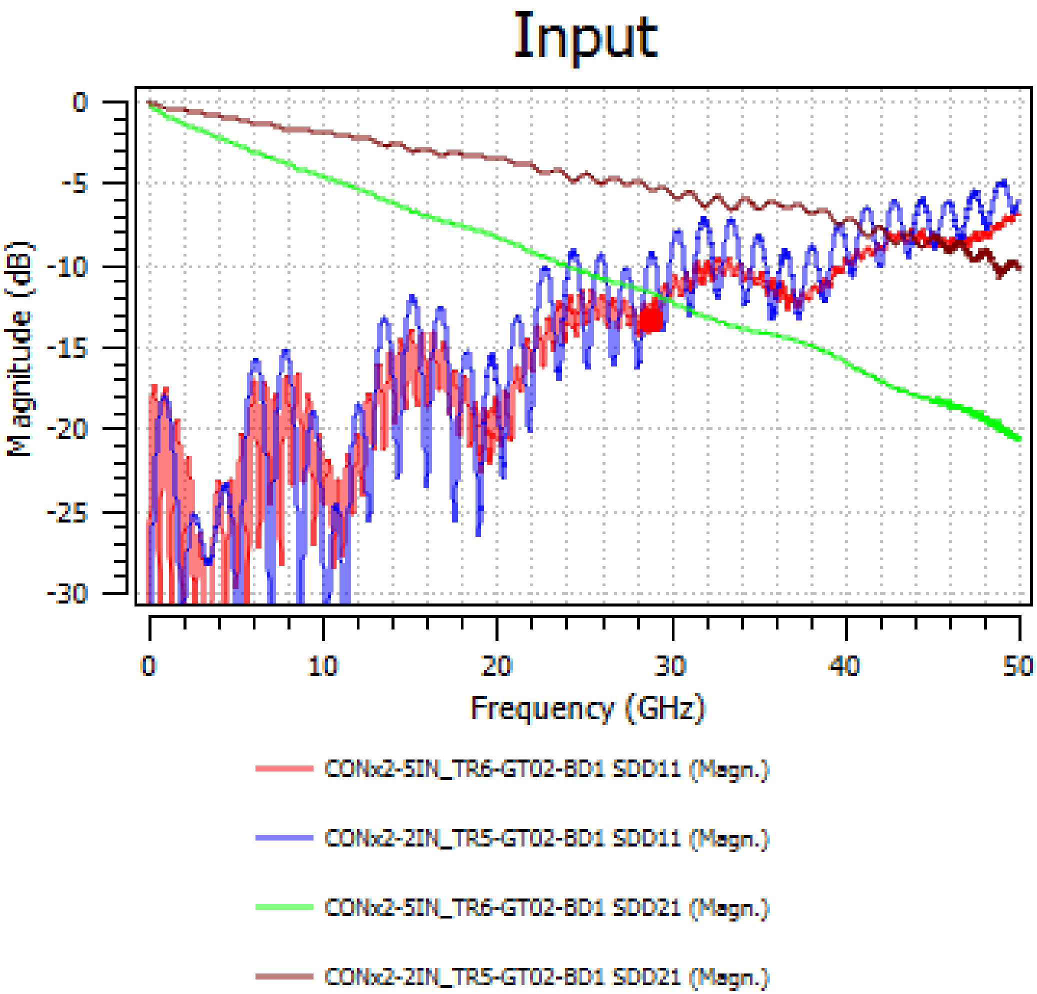
6-layer, Megtron 6, PCB, no via stubs, unknown foil, but very rough from cross-section analysis

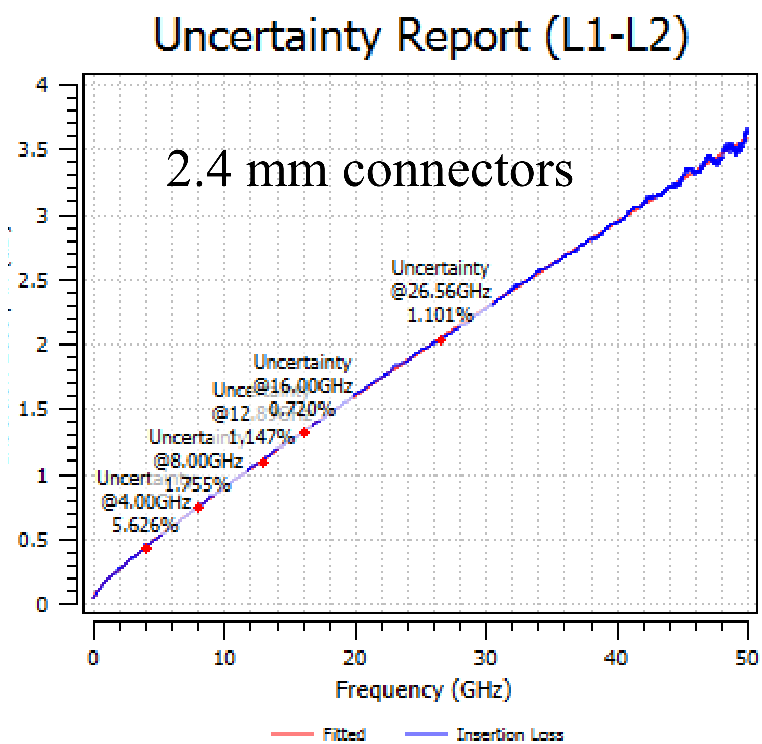




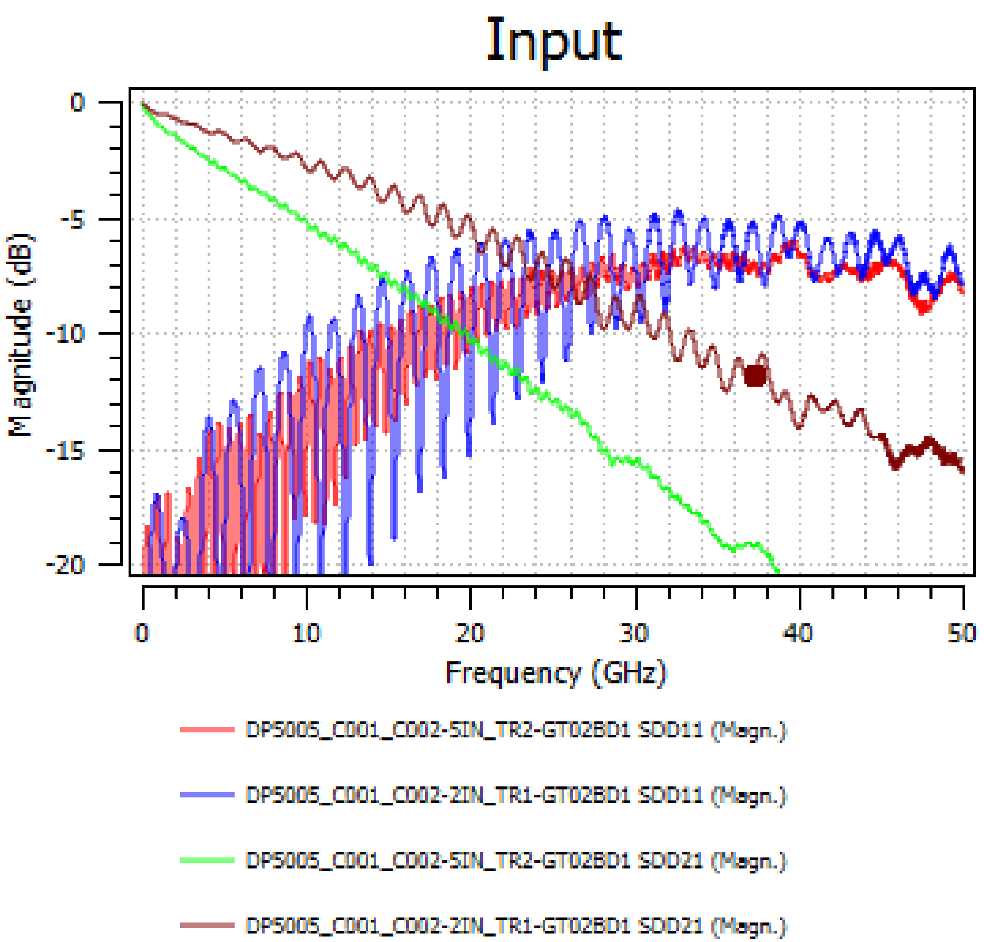
Will revisit getting this to 67 GHz later in presentation

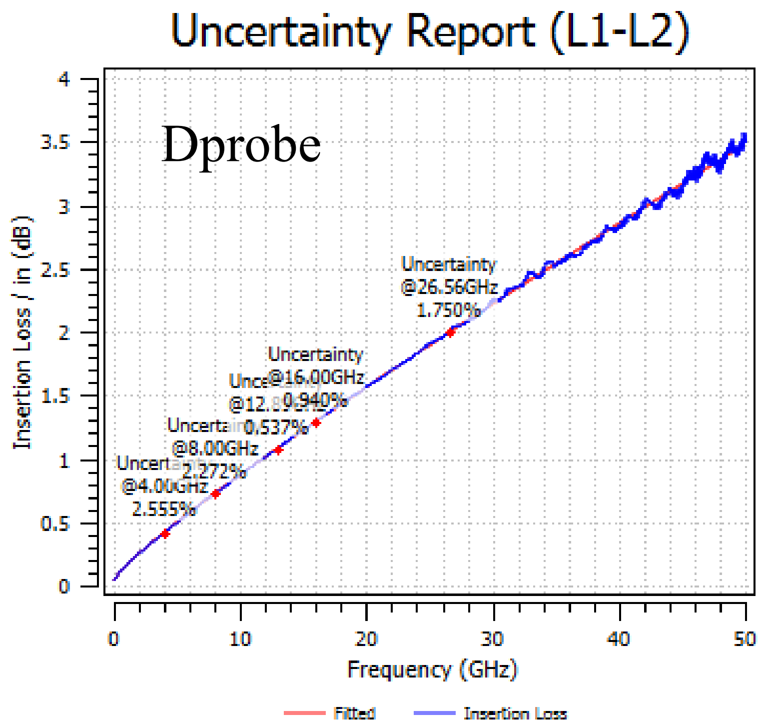
Status – 50 GHz 2.4 mm Connectors





Status – 50 GHz Dprobes





Outline

- The Intel Delta-L Methodology
  - Test methodology
  - Eigenvalue de-embedding
  - Curve-fitting insertion loss
  - Design and de-embedding essentials for achieving a high-quality outcome at high-frequencies
- Some essentials
  - Making accurate S-parameter measurements
  - Determining the reference plane for high-quality de-embedding
  - causality/passivity
- Mitigating design and layout artifacts in the curve-fitting for IL
- Moving toward 67 GHz Delta-L

Delta-L References Planes

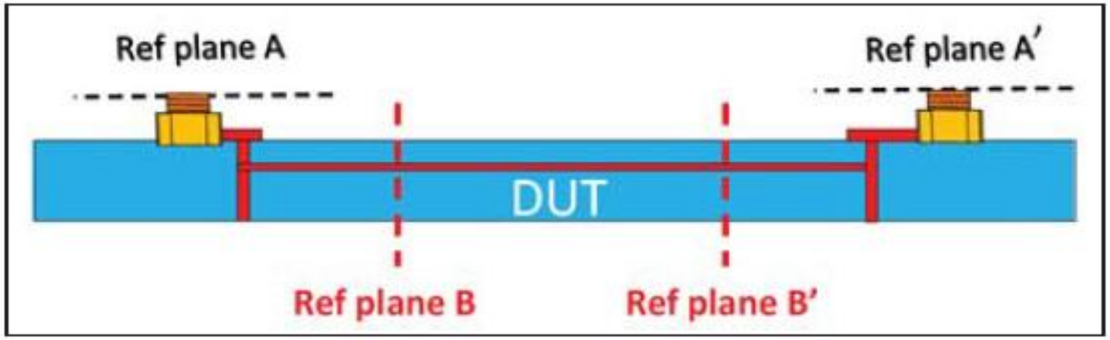


Figure 1-1 Reference Planes in Printed Board Insertion Loss Characterization

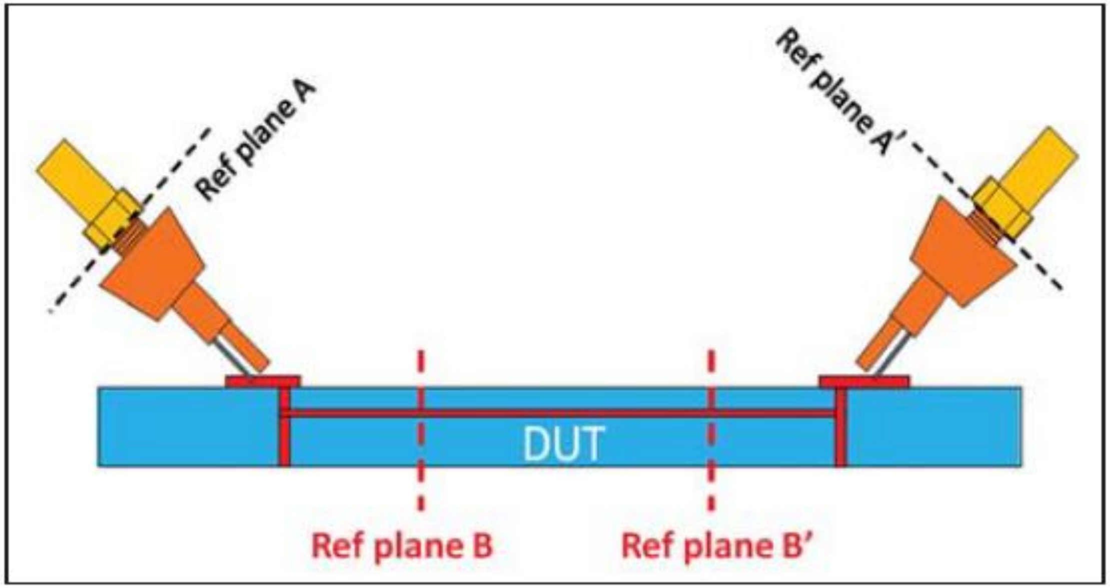


Figure 1-2 Reference Planes in Printed Board Insertion Loss Characterization with Microwave Probe

Reference planes in all cases are TEM because they are at transmission-line planes

IPC-TM-650TEST METHODS MANUAL, 2.5.5.14

Eigenvalue De-embedding Method

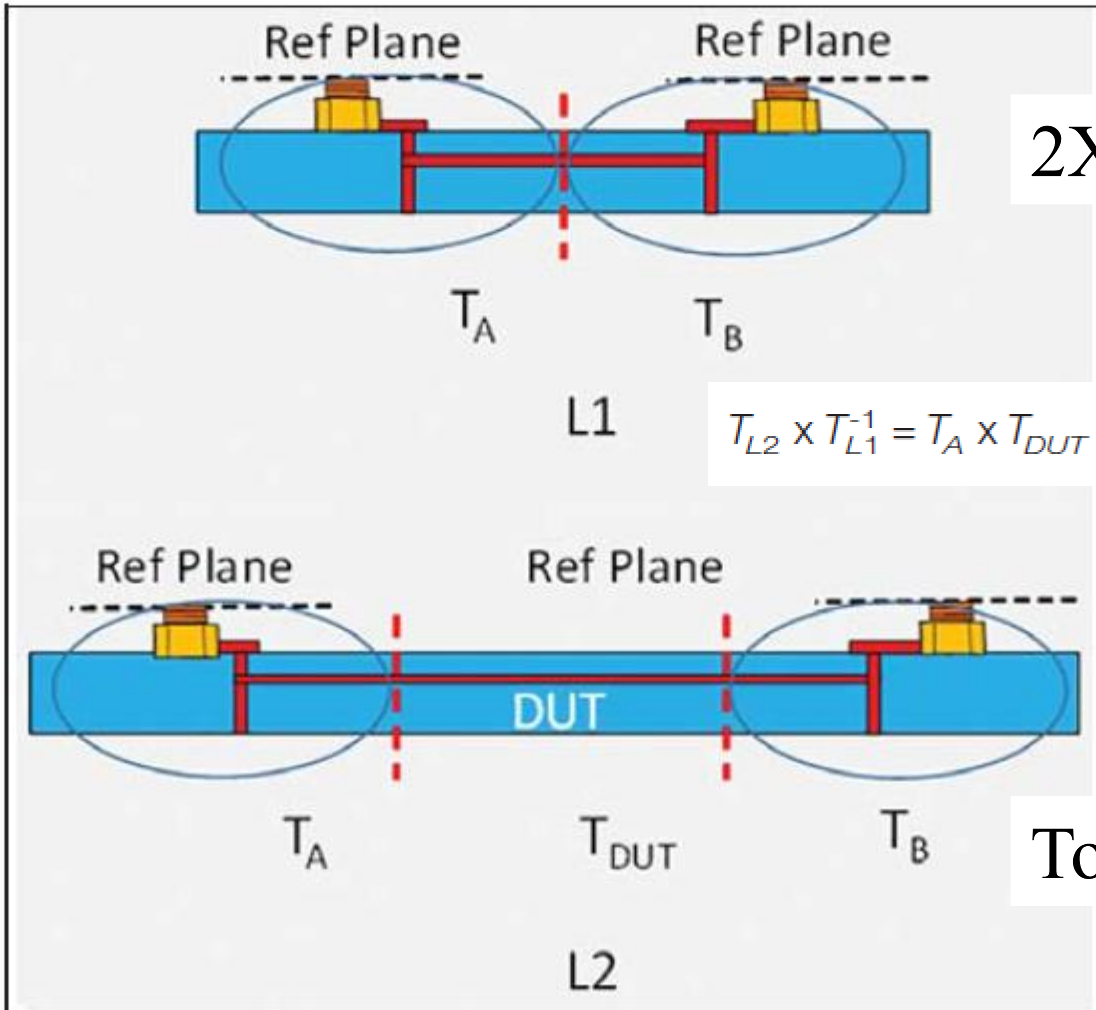


Figure 1-3 Two-line Structure for Eigenvalue-based Method

2X Thru

$$T_{L1} = T_A \times T_B \quad \text{(Eq. 2)}$$

$$T_{L2} = T_A \times T_{DUT} \times T_B \quad \text{(Eq. 3)}$$

$$T_{L2} \times T_{L1}^{-1} = T_A \times T_{DUT} \times T_B \times T_B^{-1} \times T_A^{-1} = T_A \times T_{DUT} \times T_A^{-1} \quad \text{(Eq. 4)}$$

$$T_{DUT} = \begin{bmatrix} e^{\gamma(L2-L1)} & 0 \\ 0 & e^{-\gamma(L2-L1)} \end{bmatrix} \quad \text{(Eq.5)}$$

Total structure

IPC-TM-650TEST METHODS MANUAL, 2.5.5.14

Calculation of Insertion Loss

$$T_{L1} = T_A \times T_B \quad \text{(Eq. 2)}$$

$$T_{L2} = T_A \times T_{DUT} \times T_B \quad \text{(Eq. 3)}$$

$$T_{L2} \times T_{L1}^{-1} = T_A \times T_{DUT} \times T_B \times T_B^{-1} \times T_A^{-1} = T_A \times T_{DUT} \times T_A^{-1} \quad \text{(Eq. 4)}$$

$$T_{DUT} = \begin{bmatrix} e^{\gamma(L2-L1)} & 0 \\ 0 & e^{-\gamma(L2-L1)} \end{bmatrix} \quad \text{(Eq.5)}$$

$T_{L2} \times T_{L1}^{-1}$ and T_{DUT} have the same eigenvalues.

Choose eigenvalue with absolute value <1 and real part is the attenuation.

Convert T-parameters to S-parameters:

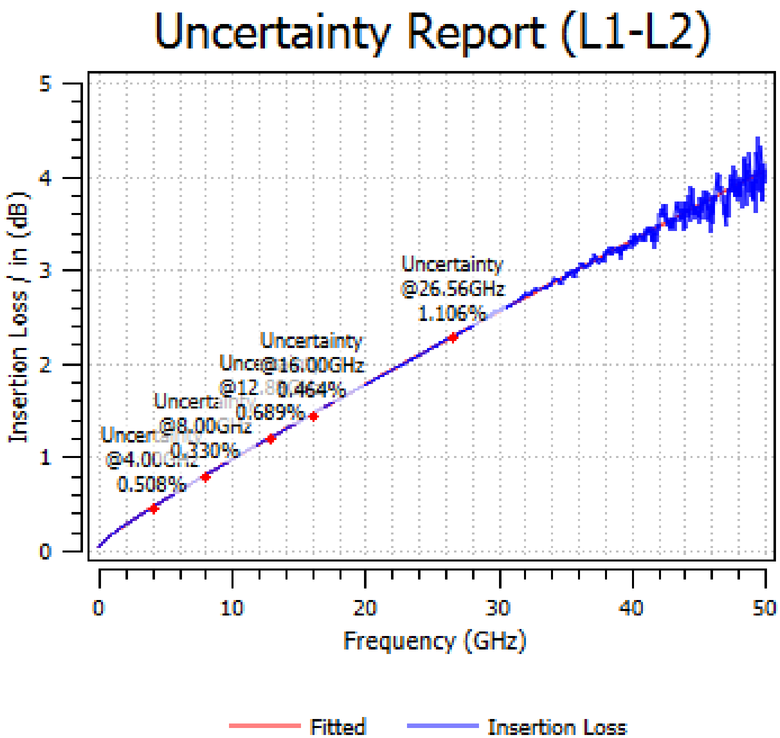
$$S_{DUT} = \begin{bmatrix} \frac{0}{e^{-\gamma L}} & \frac{e^{-\gamma L}}{0} \end{bmatrix} \quad \text{(Eq.1)}$$

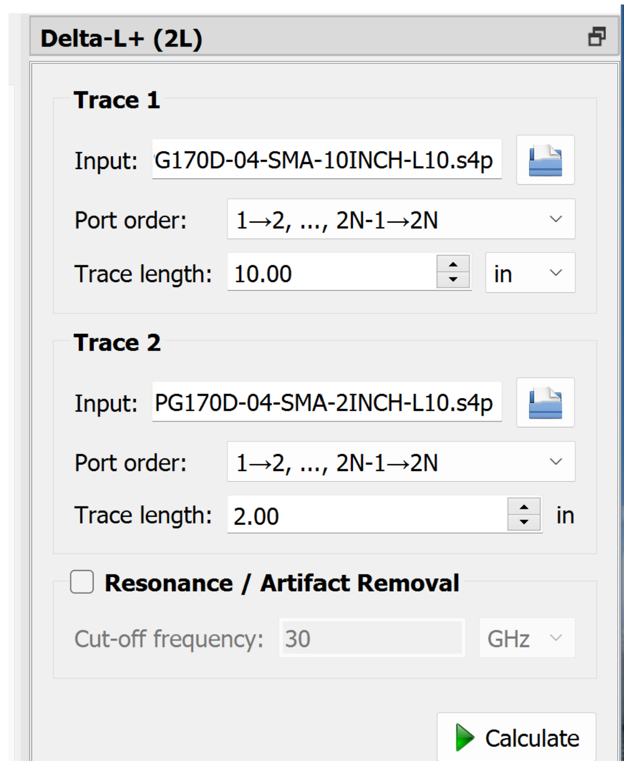
$\alpha \Rightarrow$ attenuation

$20\log_{10}(\alpha) \times length = IL$

$\gamma =$ propagation constant $= \sqrt{(R + j\omega L)(G + j\omega C)} = \alpha + j\beta$

Case 4 – Delta-L 4.0 Outcome





- IL from eigenvalue de-embedding
- Fitted IL curve according to $IL_{dB}(f) = a(f - f_0)^b + c(f - f_0)^2 + d(f - f_0) + IL_0$

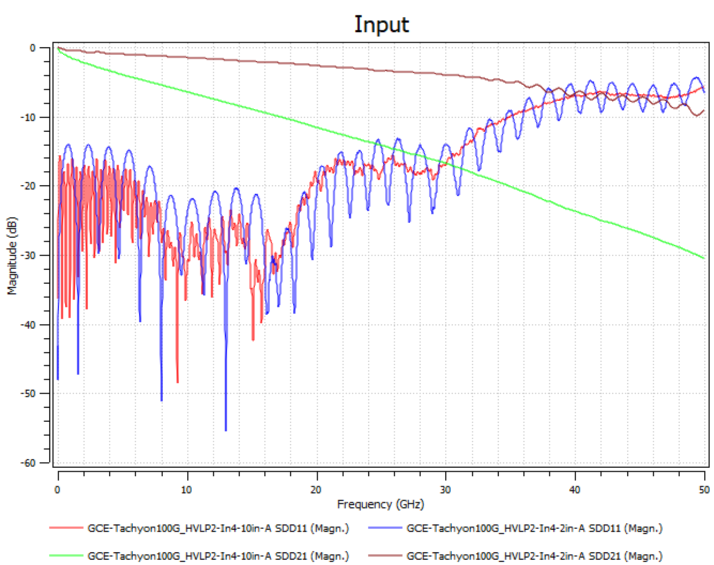
Note that above 40 GHz the de-embedding (blue curve) is becoming sensitive

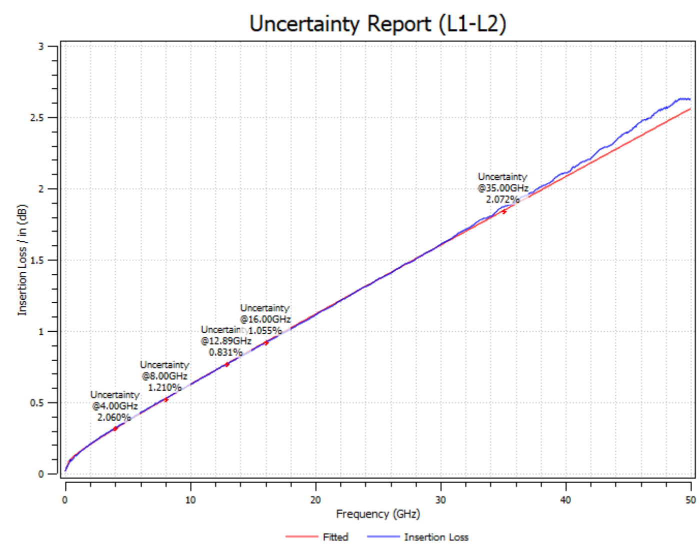
Delta-L 4.0 Curve-Fitting

$$IL_{dB}(f) = \underbrace{a(f - f_0)^b}_{\text{Conductor loss, including surface roughness}} + \underbrace{c(f - f_0)^2 + d(f - f_0)}_{\text{Dielectric loss}} + IL_0$$

IPC-TM-650TEST METHODS MANUAL, 2.5.5.14

- f_0 and IL_0 are introduced as offsets to accommodate typical 10 MHz starting points for VNA measurements
- For a perfectly smooth conductor b=0.5





Weighting Factor for Curve-Fitting

$$W(f) = \left(1 - \left(\frac{f}{f_{max}}\right)\right)^3 \quad \text{(Eq.9)}$$

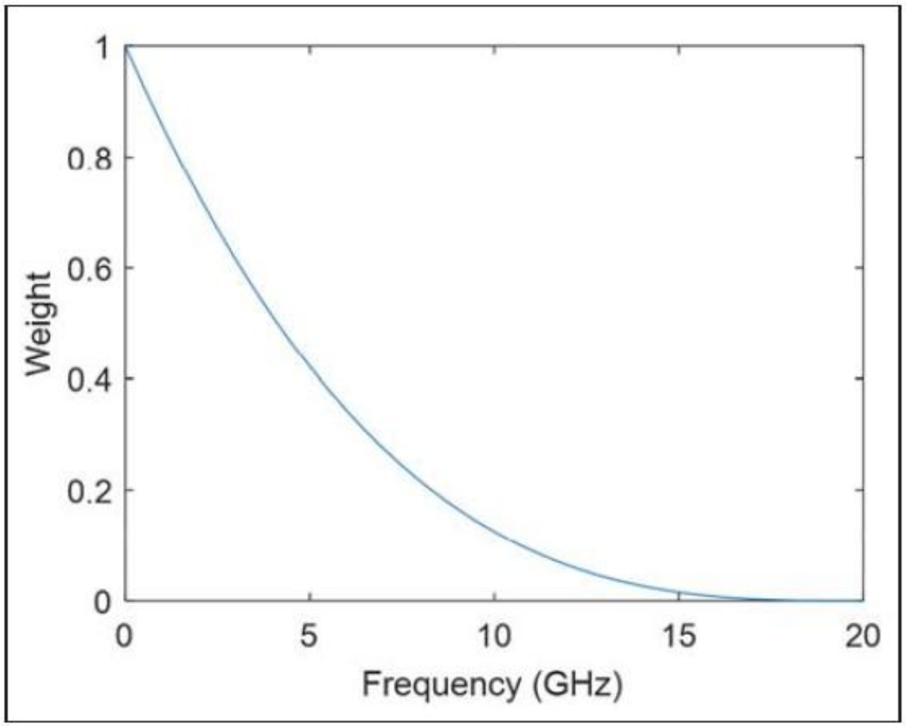


Figure 5-3 The Suggested Weight Function for Insertion Loss Curve Fitting

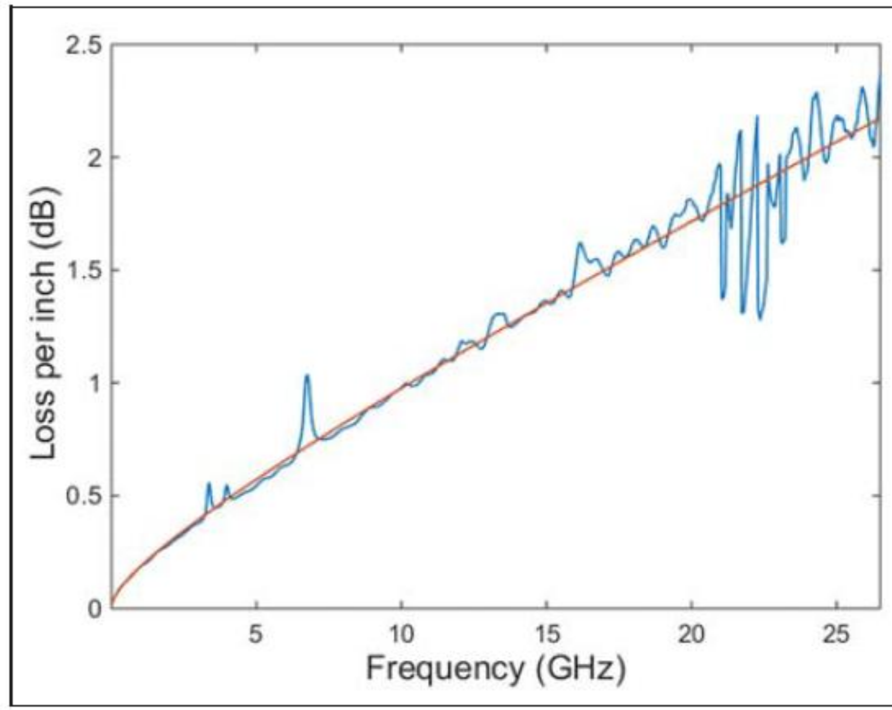
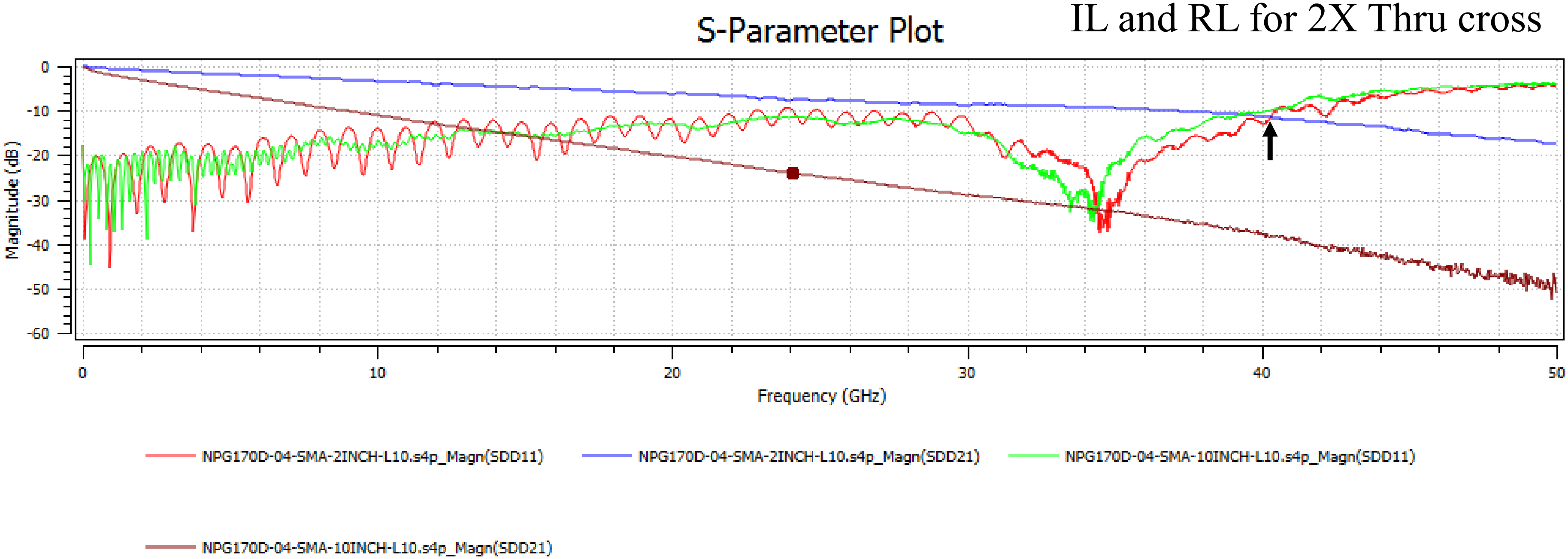


Figure 5-2 Least Squares Fit Based on (eq. 7) Applied to a Representative Insertion Loss Curve

Note 1. Red represents the fitted curve.

Case 4 – 2X Thru Meeting IEEE 370 STD to 40 GHz

IL and RL for 2X Thru cross

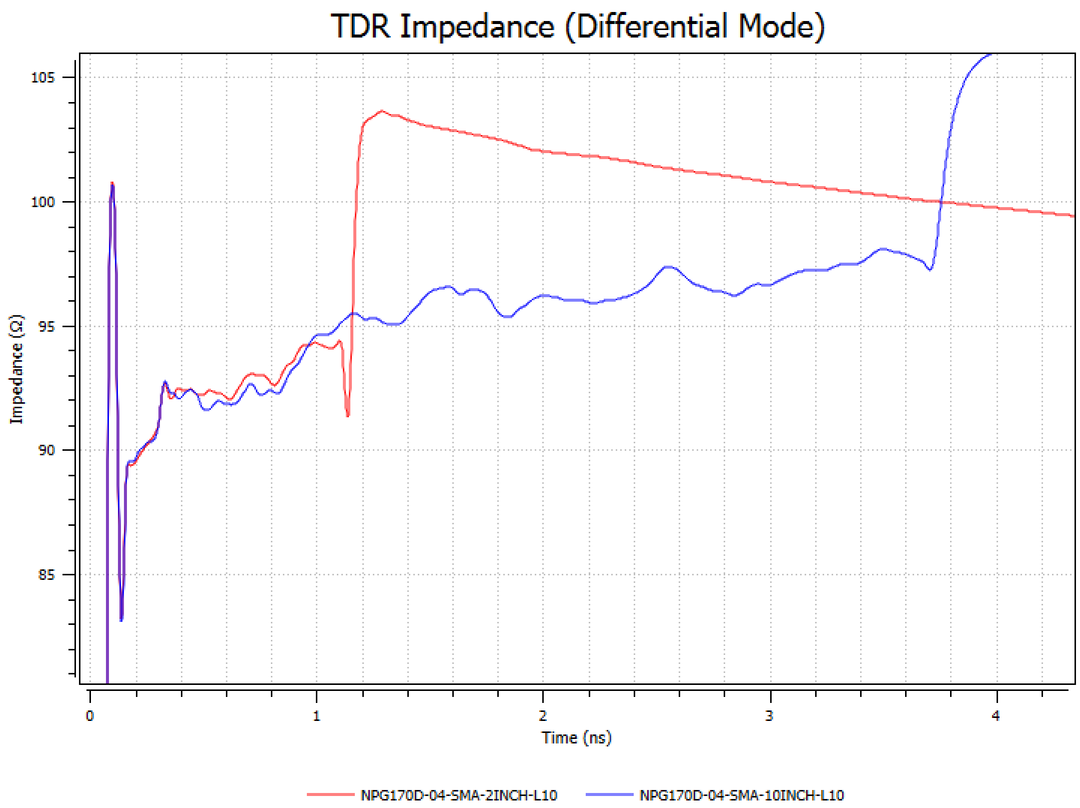


- The IL (blue) and RL (red) for the 2X Thru 2 in. stripline cross at 40 GHz
- The 2X Thru does not meet the IEEE 370 STD above and expect the de-embedding in Delta-L to become sensitive above 40 GHz with possibly resulting artifacts in the Delta-L 4.0 fit

Table 4—Fixture electrical requirement summary for mixed-mode interconnects

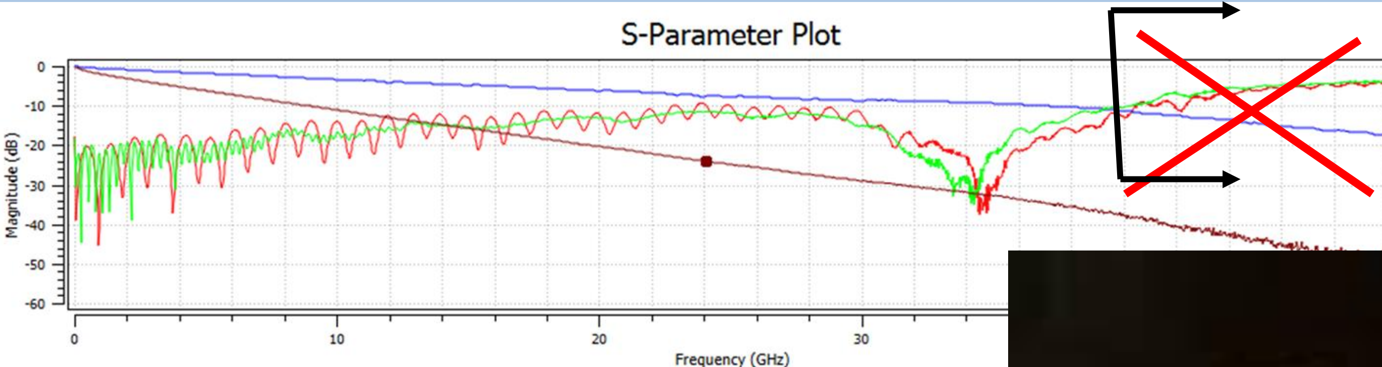
Metric	Structure	Equation	Class A limit	Class B limit	Class C limit
Insertion loss (FER1)	2X-Thru	$20 \times \log_{10} \lvert S_{DD21} \rvert$	−10 dB	−15 dB	−15 dB
Return loss (FER2)	2X-Thru	$20 \times \log_{10} \lvert S_{DD11} \rvert$	−20 dB	−10 dB	−6 dB
Difference between insertion and return loss (FER3)	2X-Thru	$20 \times \log_{10} \lvert S_{DD21} \rvert - 20 \times \log_{10} \lvert S_{DD11} \rvert$	5 dB	0 dB	0 dB

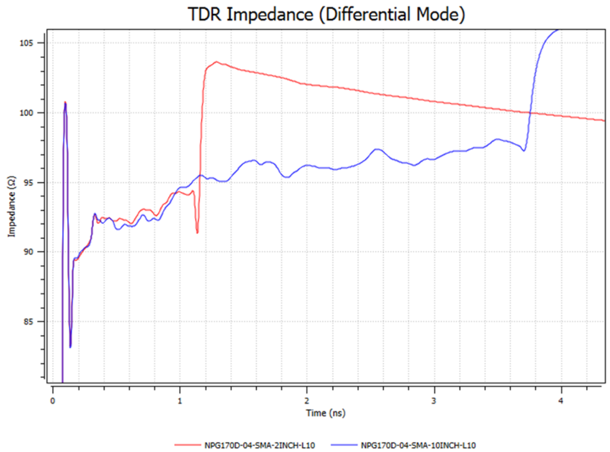
Case 4 – TDR



- The 2 in. and 10 in. traces are nearly identical in the transition and along the length. Will lead to better de-embedding and Delta-4.0 outcome.
- The transition from 100 Ω to 85 Ω is well engineered, but the stripline impedance target of 85 Ω was missed in manufacturing. If target were hit, Delta-L 4.0 outcome to 50 GHz would have been excellent.

De-Embedding is Sensitive when RL and IL of 2X Thru Cross





Crossing IL and RL of 2X Thru:

- 2X Thru is too long and IL is higher
- Transition from connector or probes not optimized resulting in higher RL at high frequencies.

Outline

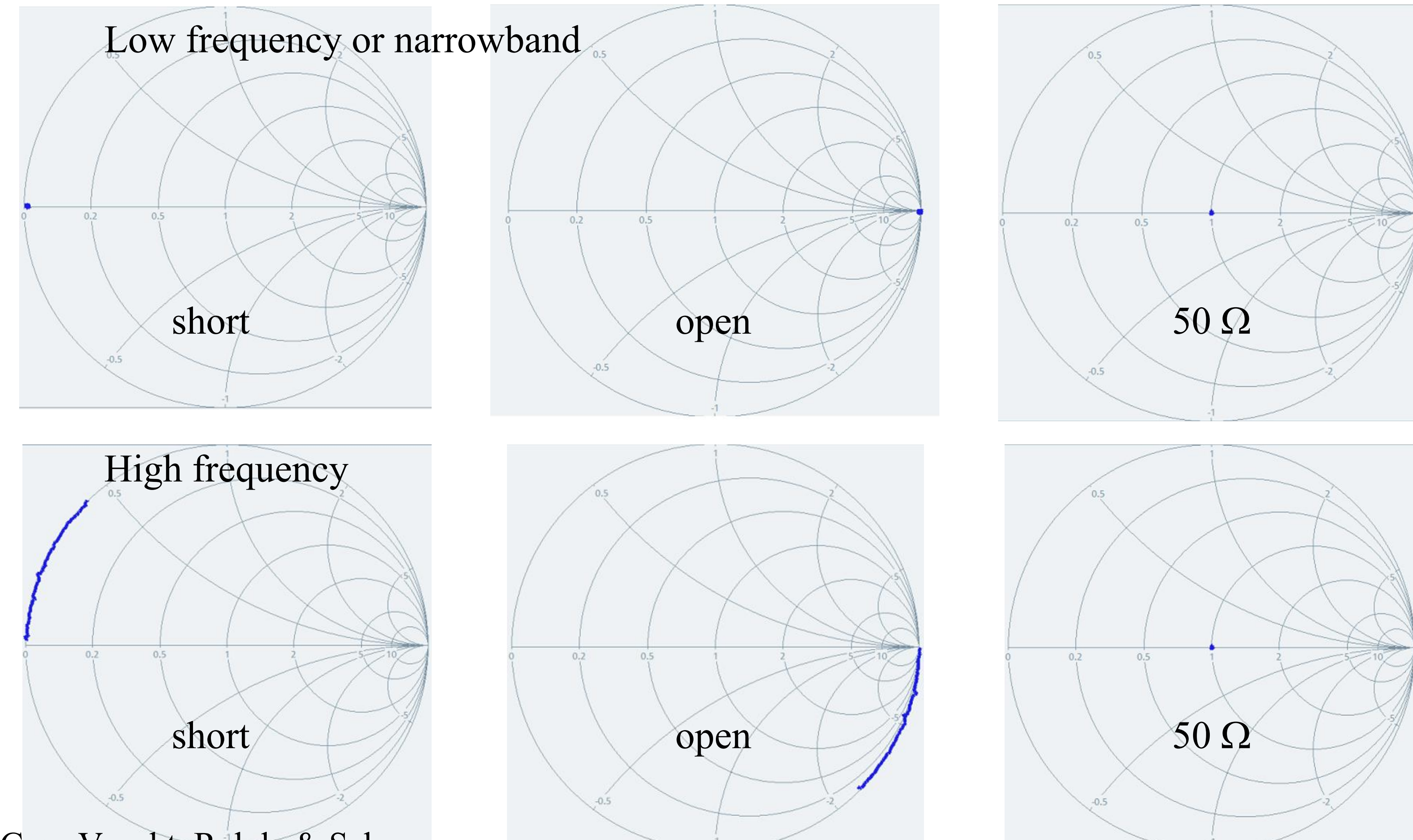
- The Intel Delta-L Methodology
  - Test methodology
  - Eigenvalue de-embedding
  - Curve-fitting insertion loss
  - Design and de-embedding essentials for achieving a high-quality outcome at high-frequencies
- Some essentials
  - Making accurate S-parameter measurements
  - Determining the reference plane for high-quality de-embedding
  - causality/passivity
- Mitigating design and layout artifacts in the curve-fitting for IL
- Moving toward 67 GHz Delta-L

Making Accurate S-parameter Measurements

- **Suitable high-frequency cables with precision connectors and precision adapters that are clean, maintained and not worn**
- **Have a mechanically stable measurement setup and avoid movement of cables and the DUT – plan the layout**
- Proper calibration coefficients for the cal kit
- Only the connector nut should be moving when mating a connector pair.
- Use proper torque wrenches
- Warm up the VNA per manufacturer's specs before calibrating and measuring
- Calibrate the VNA immediately prior to measurements
- Use cal kits with care – they are relatively fragile, and regularly have them re-characterized per specs

Sanity Checks for Calibration

- Put the calibration standards back on and view on the Smith Chart to ensure that short, open, and load calibrations are “true” *

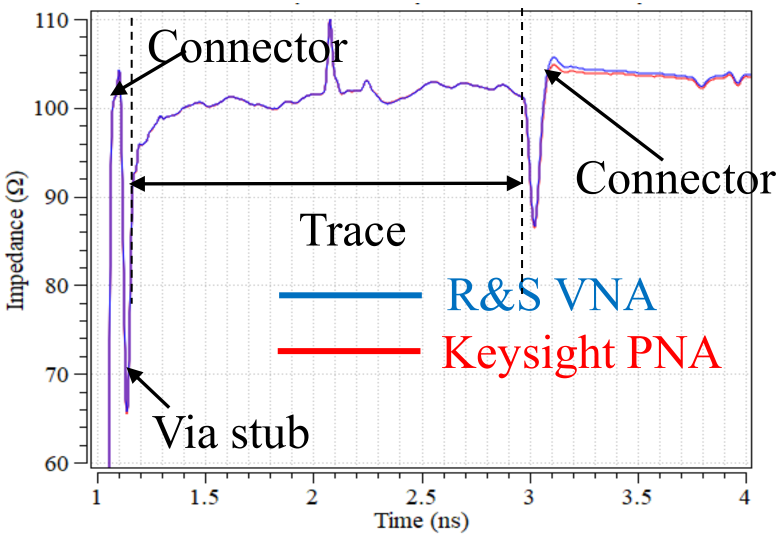


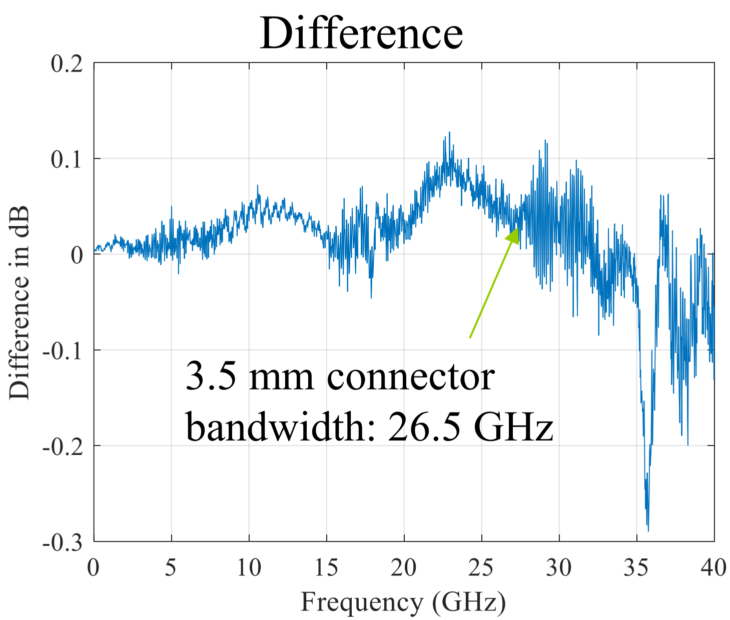
*Greg Vaught, Rohde & Schwarz

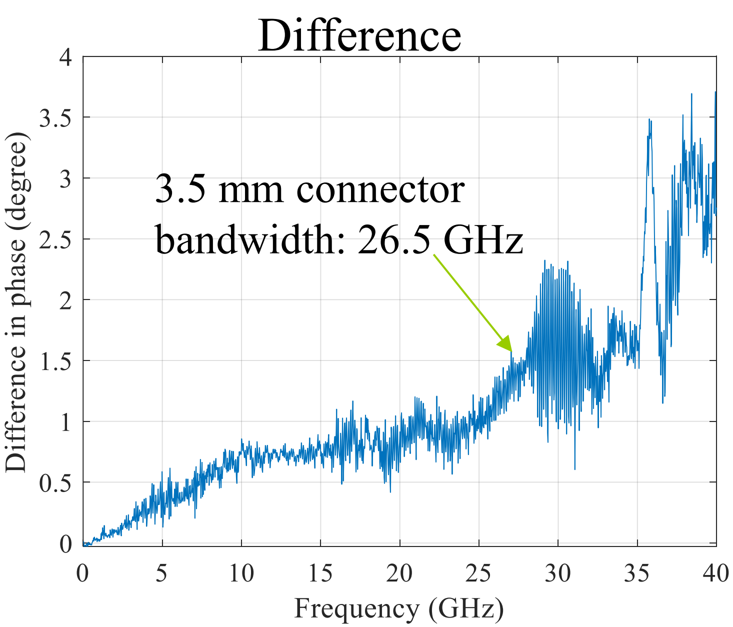
Comparison of Two Different Vendor VNAs

Rohde & Schwarz ZNB 40
(100KHz – 40GHz)

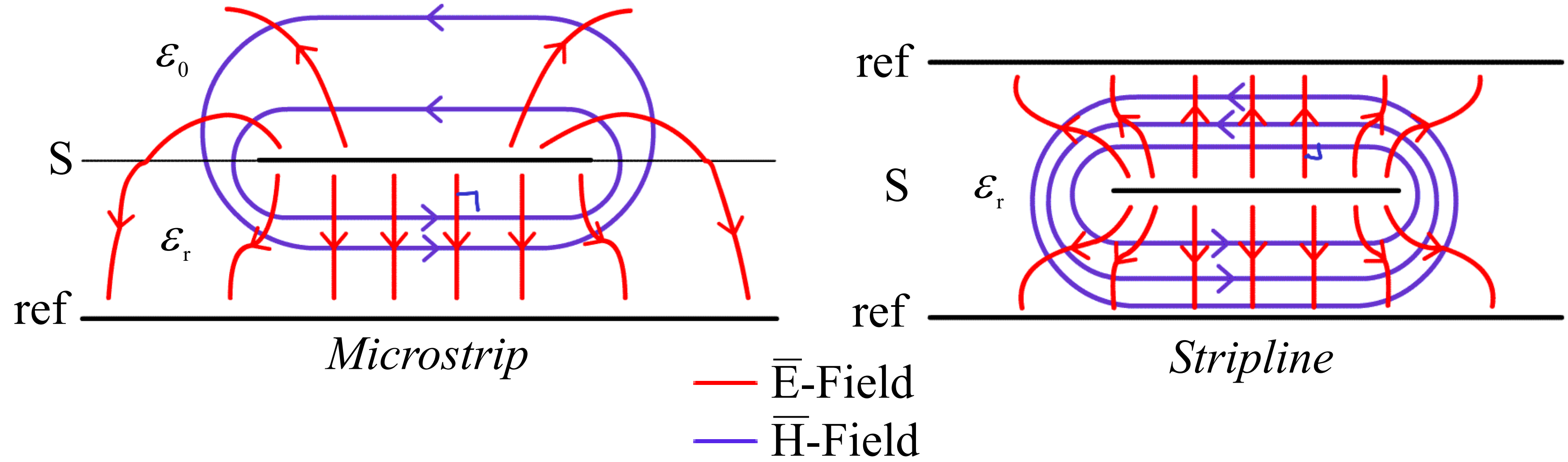
Two adaptors are used, a 2.4 M to 3.5 F, and a 3.5M to 3.5 M.





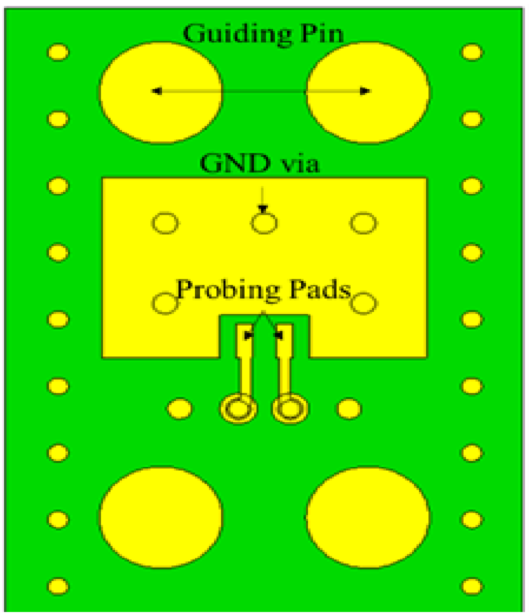


TEM – Transverse Electromagnetic Propagation



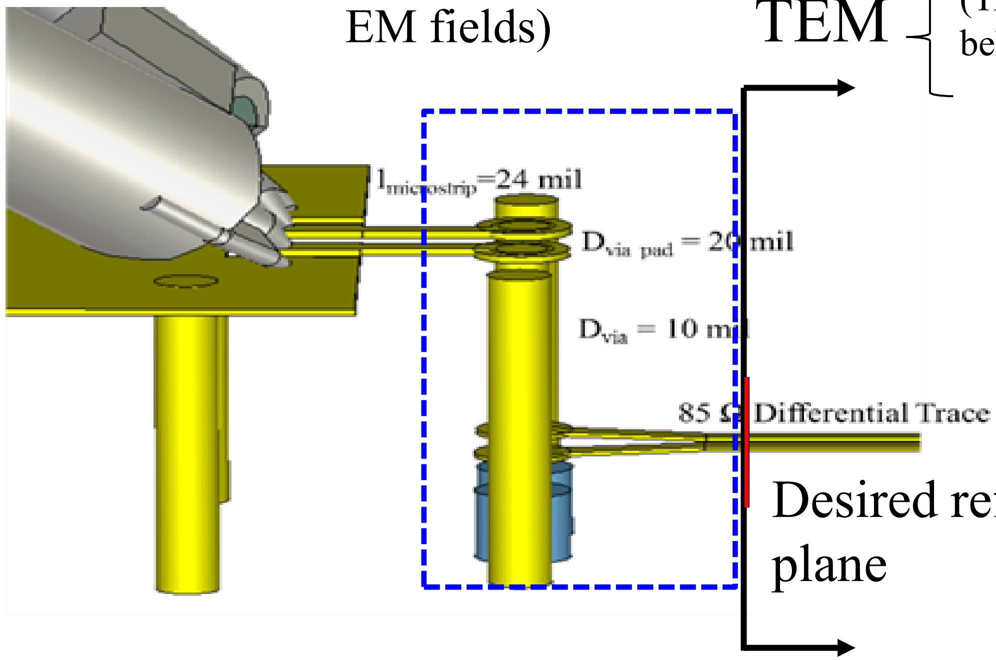
- **Transverse Electromagnetic (TEM) waves have the electric- and magnetic-field lines perpendicular, and E x H is in the direction of propagation.**
- **The geometry for a TEM transmission-line is translationally invariant, i.e., at every point along the length of the propagation, the cross-section geometry is the same**
- TEM waves have the property that the wave speed is the same for all frequencies (no dispersion for the ideal lossless case R = G = 0).
- Stripline supports a <u>pure</u> TEM wave (though PCB stripline is technically not pure TEM, but quasi-TEM), but microstrip is <u>quasi</u>-TEM.

TEM Boundary for Probing



not TEM (higher-order EM fields)

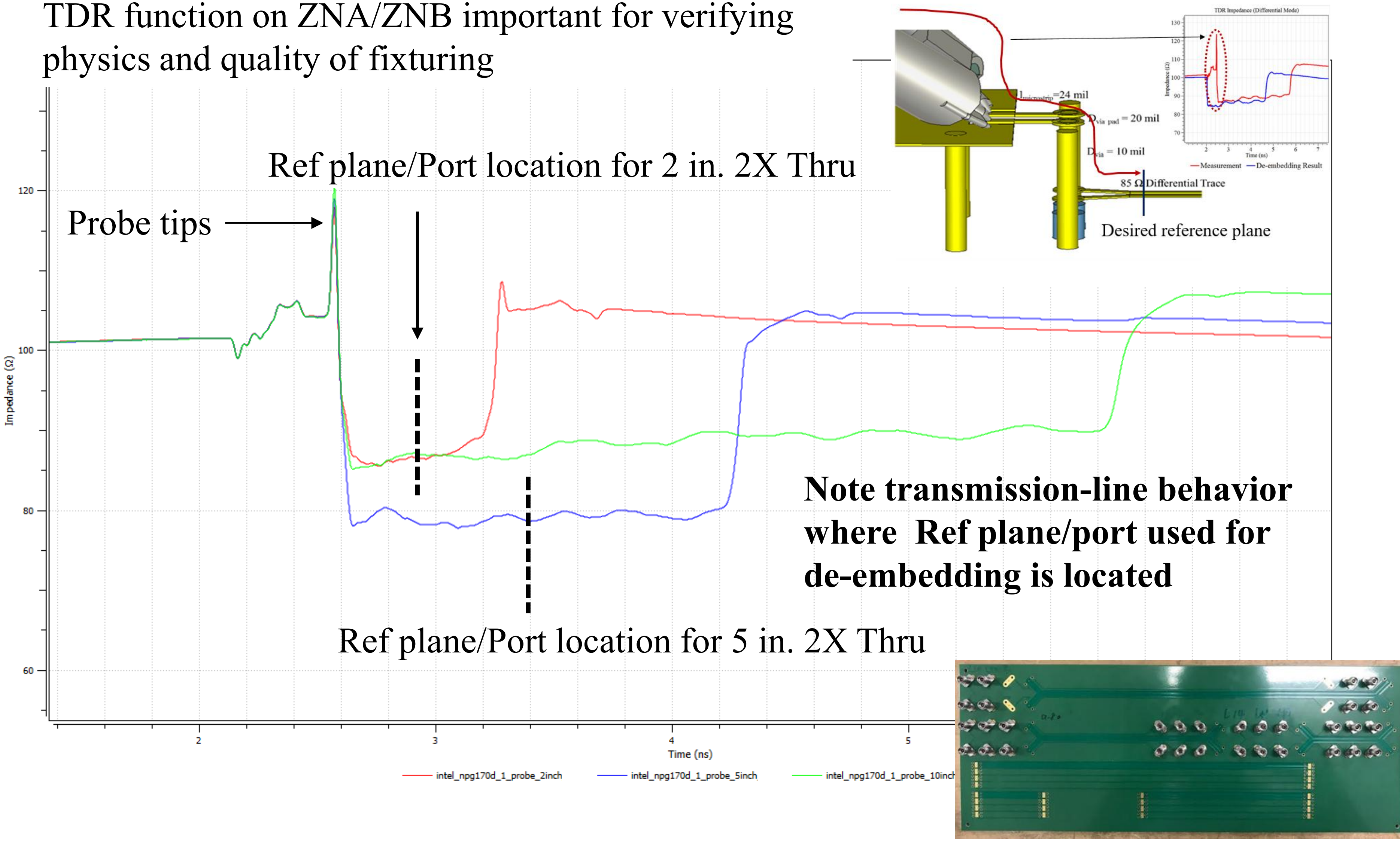
TEM (Transmission-line behavior)



Desired reference plane

TDR for 2”, 5”, 10” for 85 Ω Differential Pair

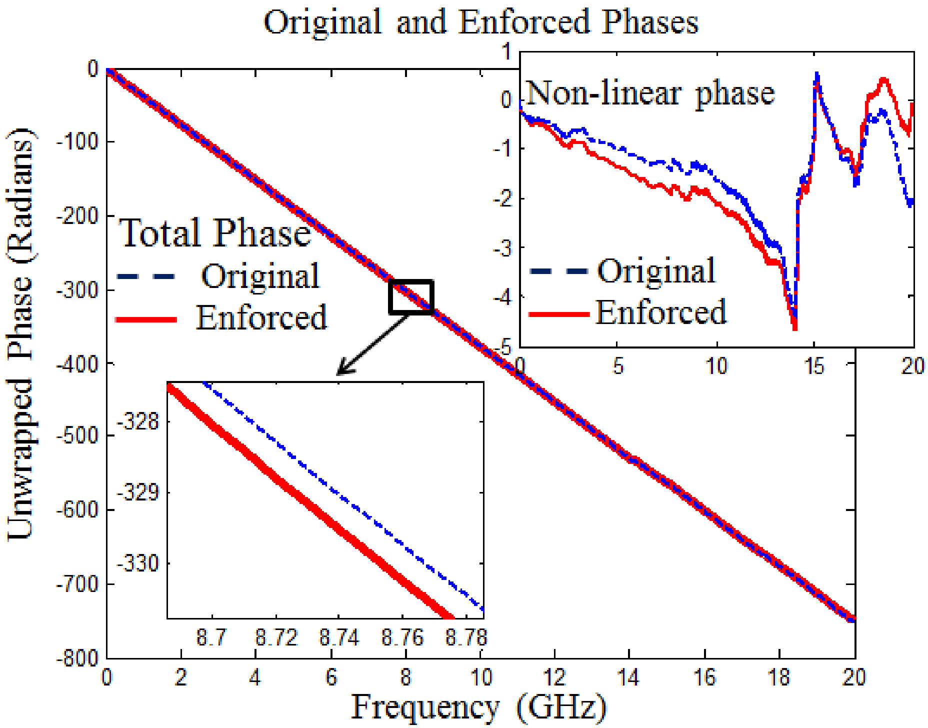
TDR function on ZNA/ZNB important for verifying physics and quality of fixturing

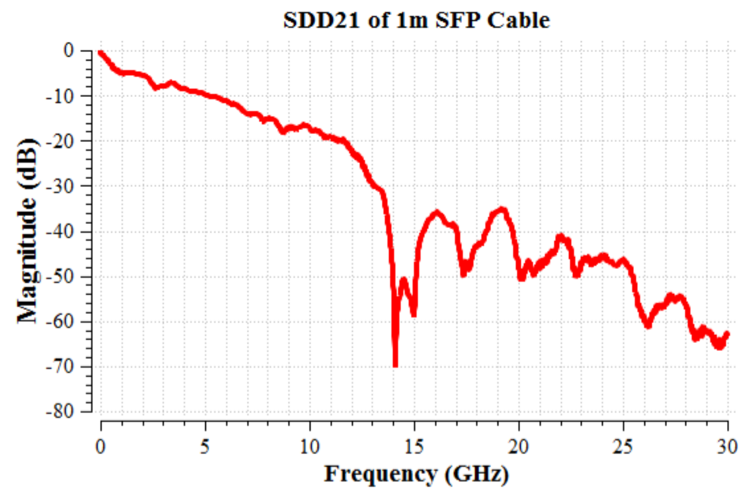


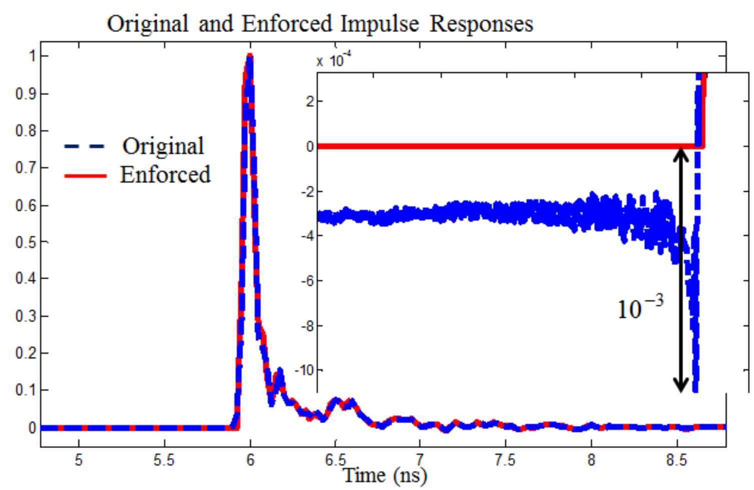
S-Parameters– Causality and Passivity Check

Causality and passivity should always be checked for S-parameters. (functionality provided in AITT)

- Measured 1m SFP cable
- Maintain magnitude and enforce phase for causality, or re-measure







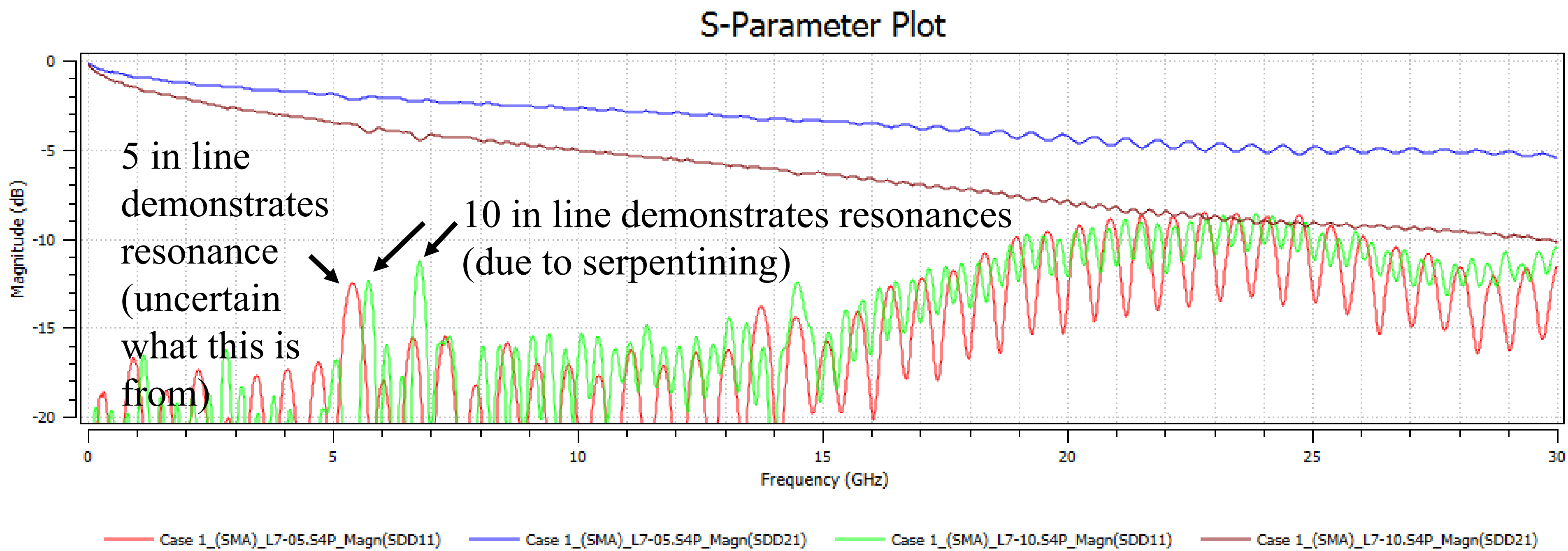
Outline

- The Intel Delta-L Methodology
  - Test methodology
  - Eigenvalue de-embedding
  - Curve-fitting insertion loss
  - Design and de-embedding essentials for achieving a high-quality outcome at high-frequencies
- Some essentials
  - Making accurate S-parameter measurements
  - Determining the reference plane for high-quality de-embedding
  - causality/passivity
- Mitigating design and layout artifacts in the curve-fitting for IL
- Moving toward 67 GHz Delta-L

Layout and Artifacts

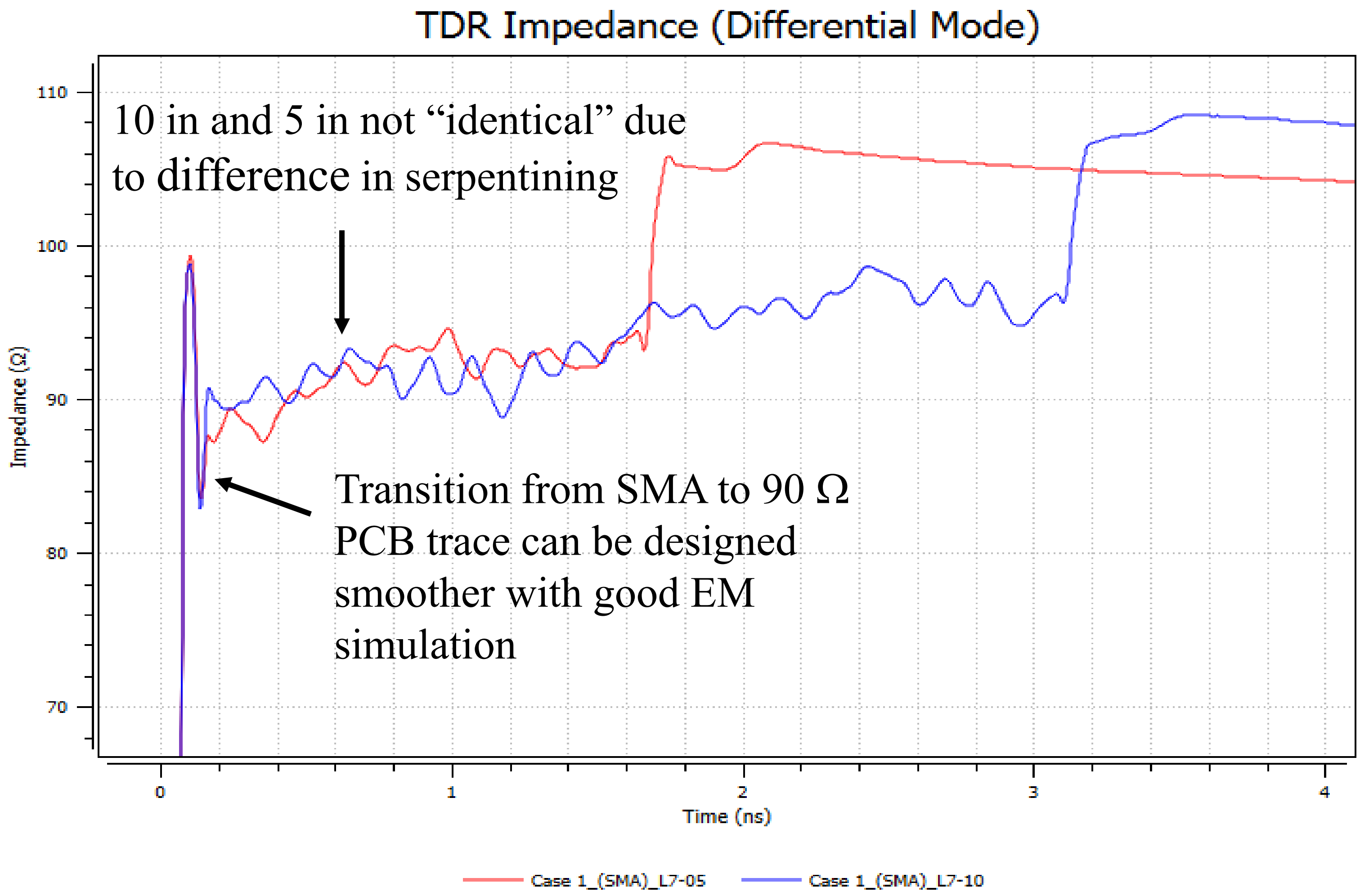
- Layout features can cause artifacts and resonances
  - Serpentining long traces leads to resonances
  - Insufficient ground vias at signal layer transitions can lead to a parallel-plate resonance that couples to the stripline being measured
- Best practices
  - Straight traces (at 67 GHz shorter traces will be necessary anyway and save space)
  - Universal footprint that ensures good signal return (GND) at the via transition – development underway with Intel
  - Via stitching that is randomized around a nominal spacing

Case 1 – Resonances Due to Serpentining: S-Parameters



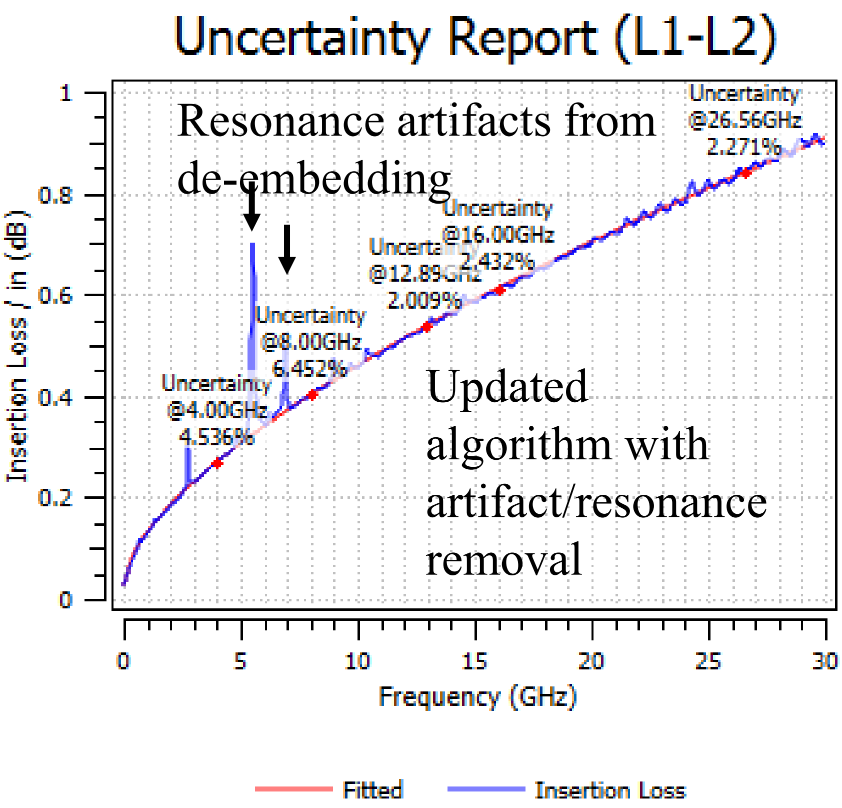
- S-parameter data shows that design of transition to PCB from an SMA is fairly good
- S-parameter data meets IEEE 370 STD for de-embedding
- Resonances in data will be reflected in de-embedding and must be dealt with in loss fitting

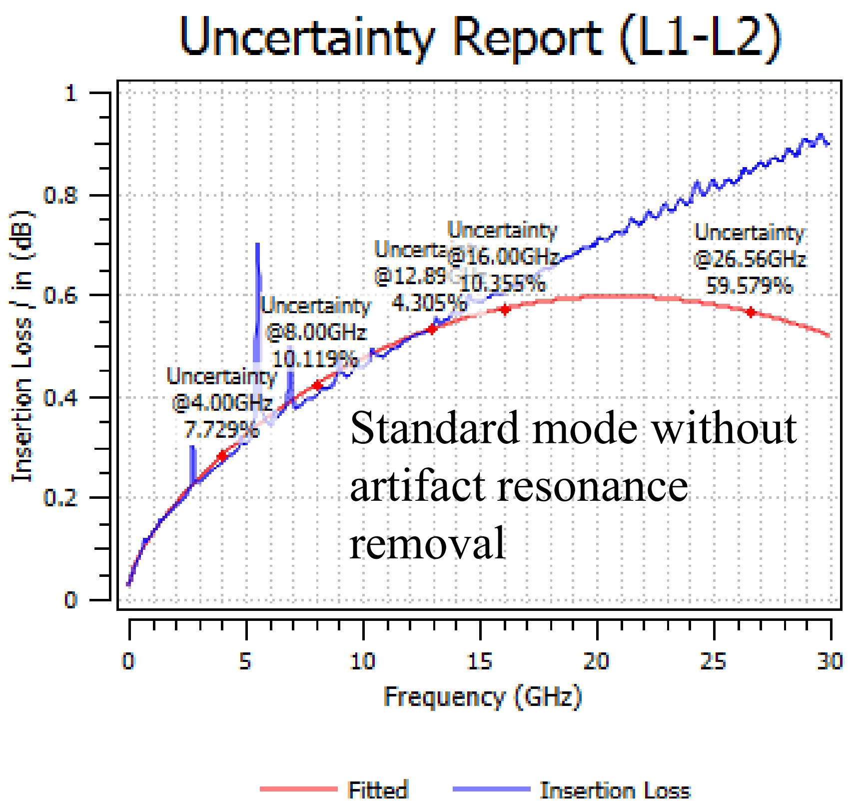
Case 1 – Differential TDR



Case 1 – Delta-L 4.0 with & w/o Resonance/Artifact Removal

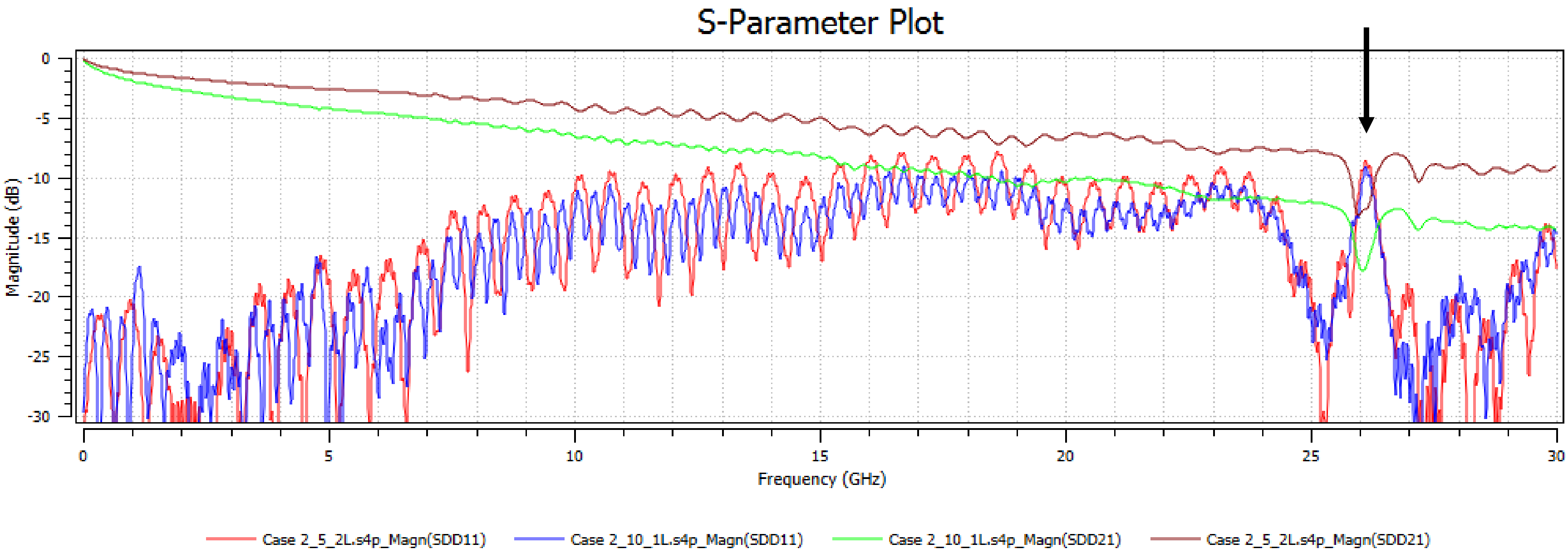
Have developed in AITT a curve-fitting routine that eliminates resonance and artifact skewing in the curve fitting





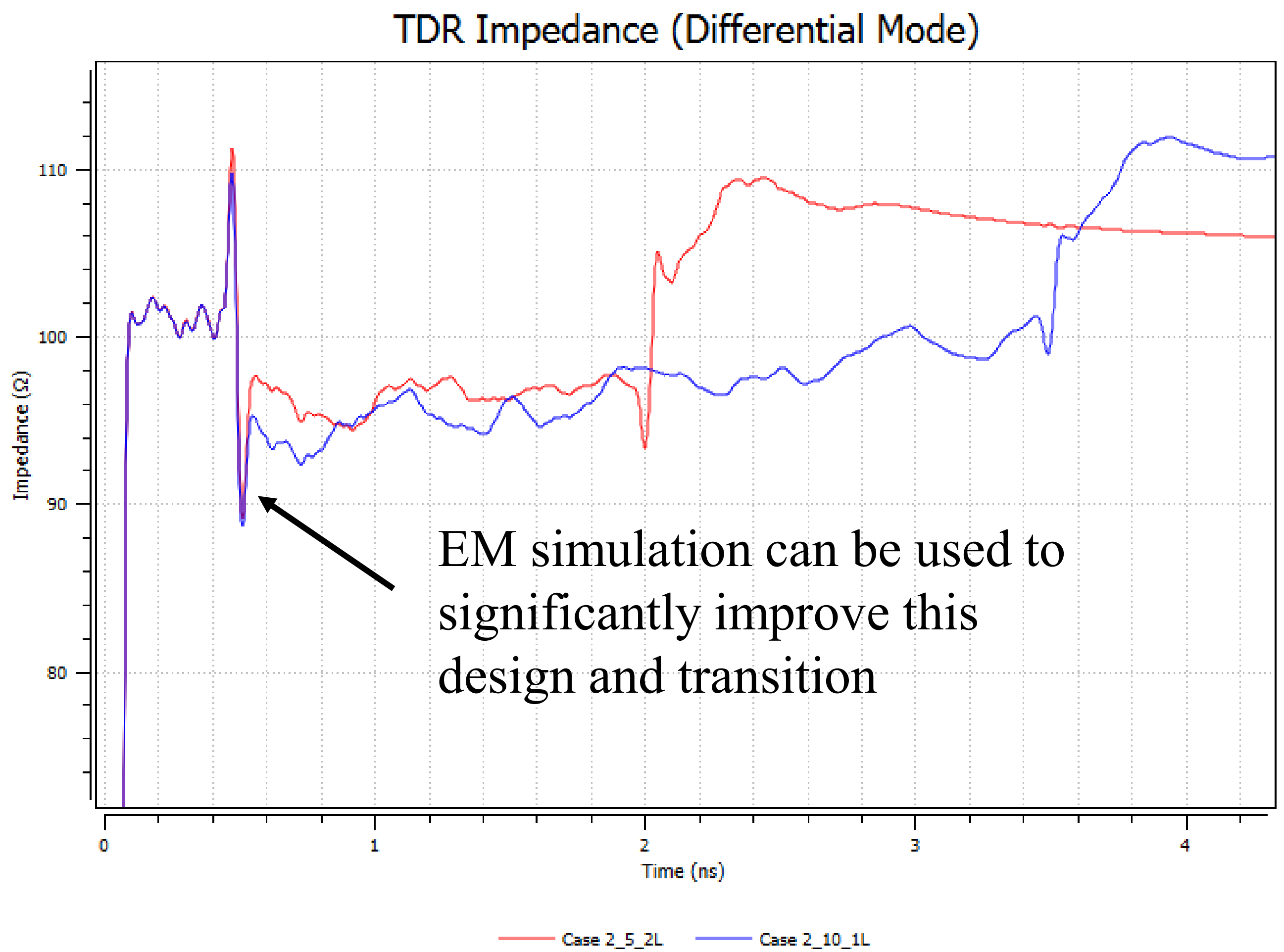
Case 2 – Coupling to Planes from Via Transition at Feed: S-Parameters

Resonance due to via transition at feed coupling to parallel-plate modes



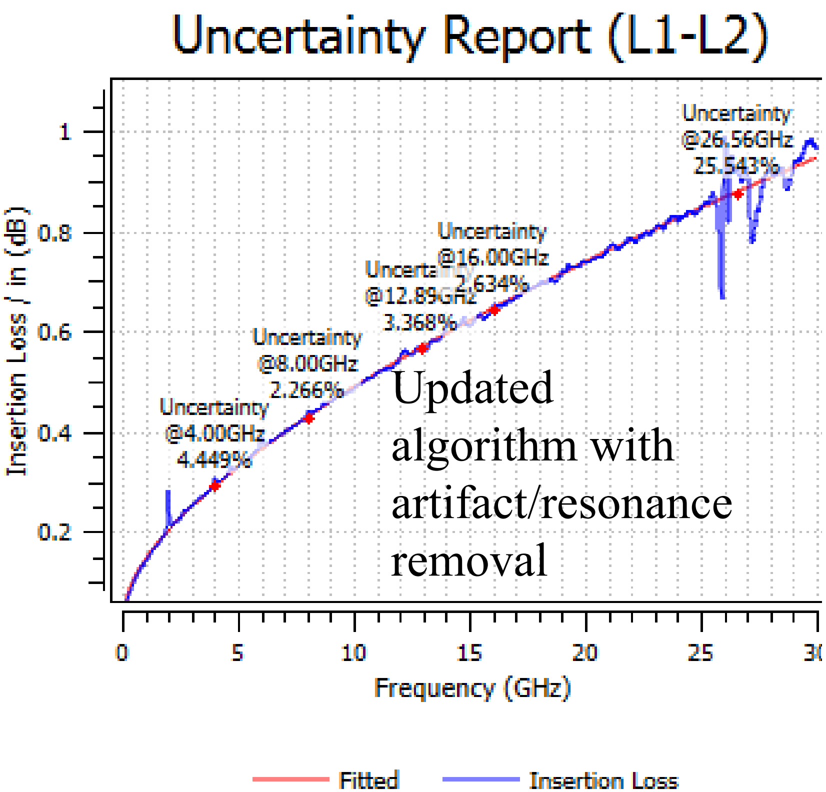
- Resonance due to via transition coupling to parallel plate modes will result in de-embedding sensitivity
- Crossing of IL and RL in the shorter 2X Thru (brown, red curves) will result in de-embedding sensitivity
- EM simulation can be used here to identify this resonance, its cause, and solution

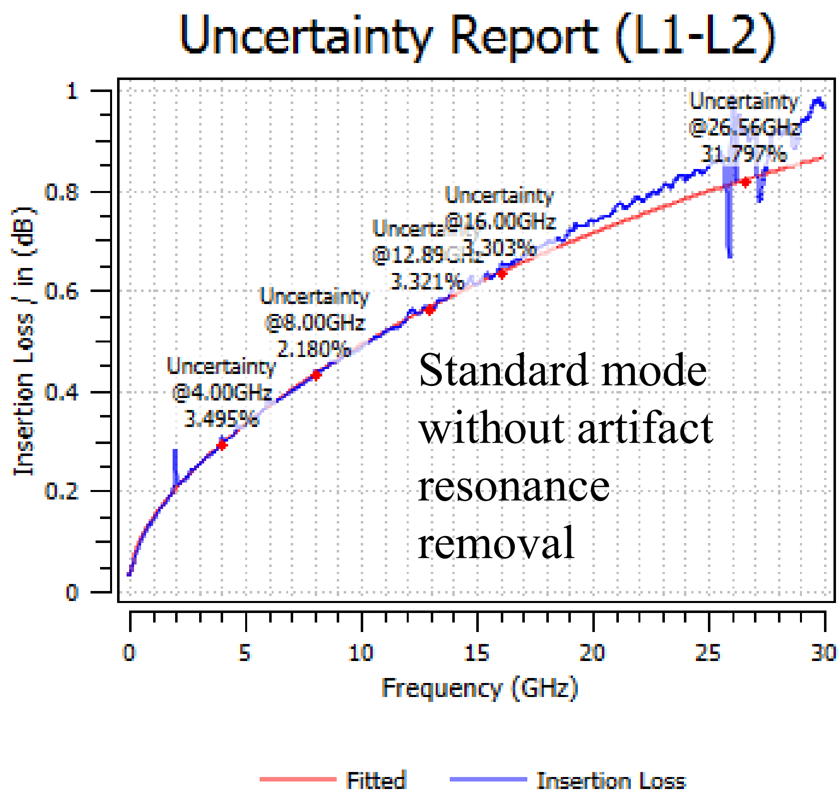
Case 2 - TDR



Parallel plate mode coupling to the signal trace is not readily apparent in the TDR

Case 2 - Delta-L 4.0 with & w/o Resonance/Artifact Removal

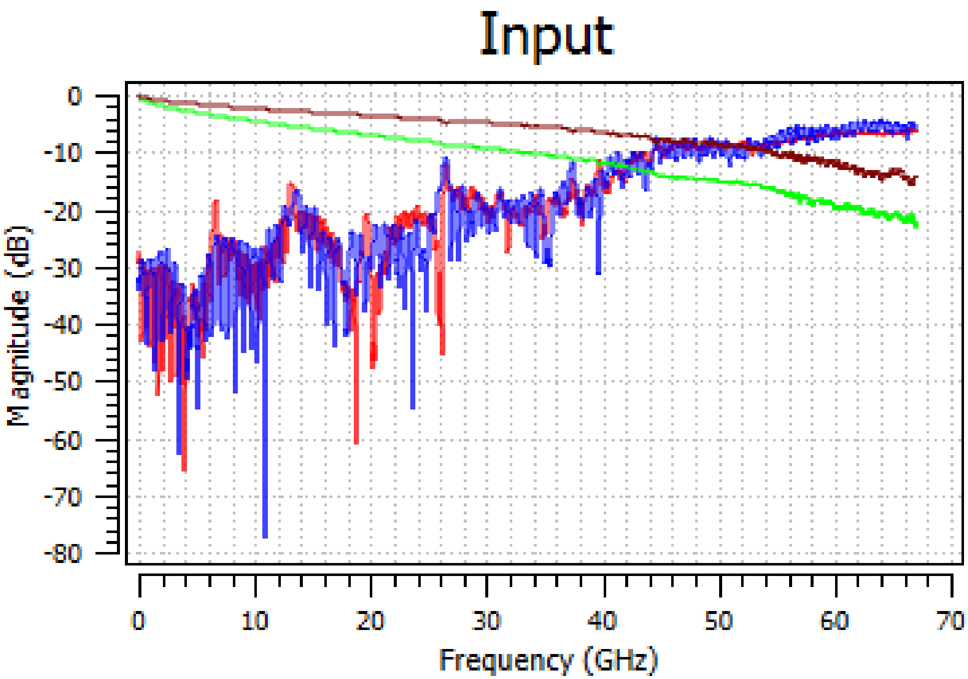


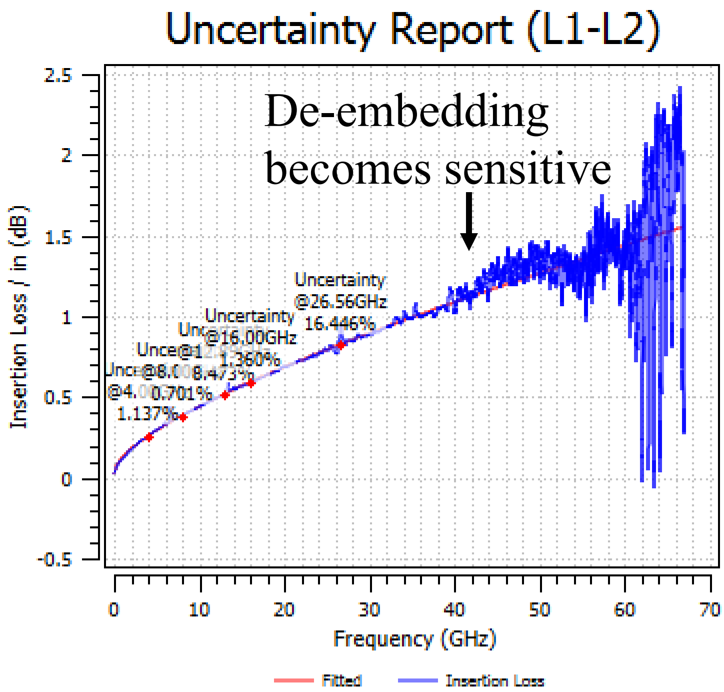


Outline

- The Intel Delta-L Methodology
  - Test methodology
  - Eigenvalue de-embedding
  - Curve-fitting insertion loss
  - Design and de-embedding essentials for achieving a high-quality outcome at high-frequencies
- Some essentials
  - Making accurate S-parameter measurements
  - Determining the reference plane for high-quality de-embedding
  - causality/passivity
- Mitigating design and layout artifacts in the curve-fitting for IL
- Moving toward 67 GHz Delta-L

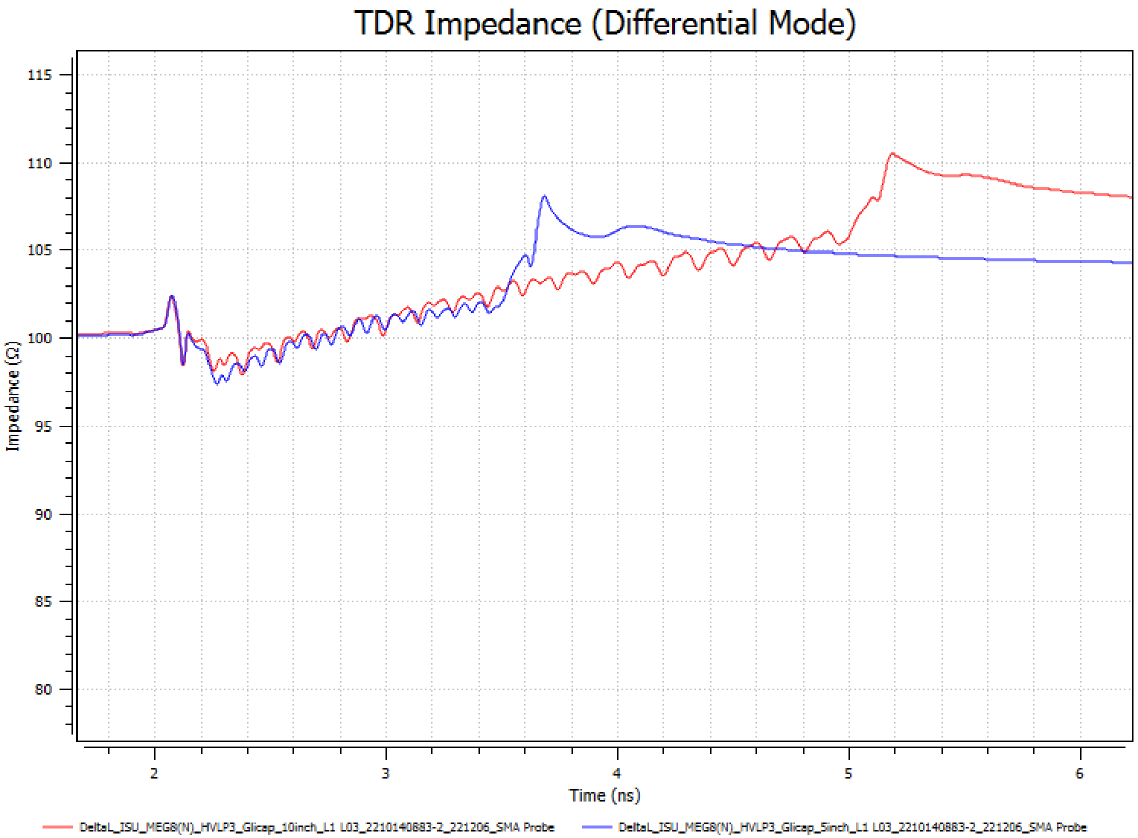
67 GHz Test Vehicle with Connectors





- 2X Thru does not meet IEEE 370 STD – RL and IL cross at 44 GHz
- 5” too long for 2X Thru
- RL looks to be adequate to 67 GHz, and 1” for 2X Thru would be better
- De-embedding sensitive where IL and RL of 2X Thru cross as seen in Delta-L

67 GHz Test Vehicle TDR

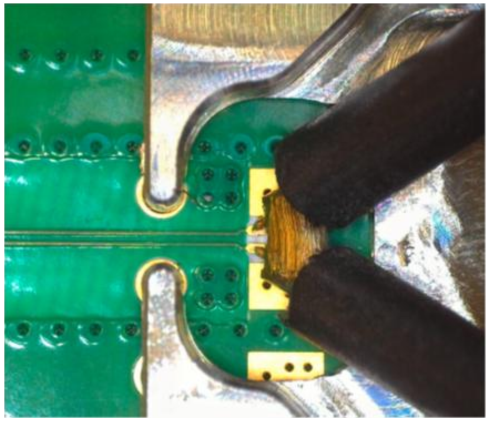


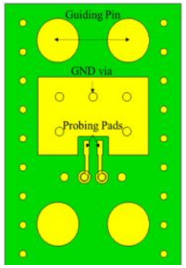
- Design of connector transition good
- Periodicity in both 5” and 10” lines unknown (have only data from customer).
- Periodic in time indicates a discrete resonance frequency, may be due to periodic via stitching. Via-stitching should be randomized about an average value.
- Could be fiber-weave.

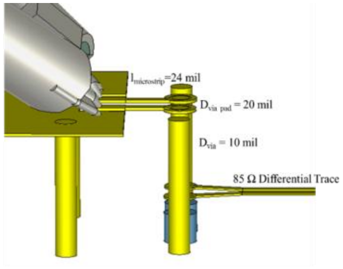
Summary for Achieving Delta-L to 67 GHz

- Use hand-held probes for use in large-volume measurements and in fabrication environment
- Must have optimized universal footprint to accommodate handheld probes and rapid alignment/placement
- 0.4 mm most likely a minimum probe pitch for rapid alignment due to manufacturing tolerance in PCB fab
- Must consider deviating from the legacy 2”, 5”, 10” patterns for Delta-L, e.g., 1”, 6” to meet IEEE 370 STD for de-embedding accuracy

Universal Probe Launch with PacketMicro Probes





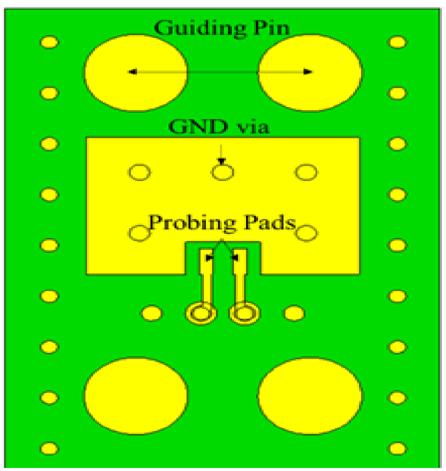


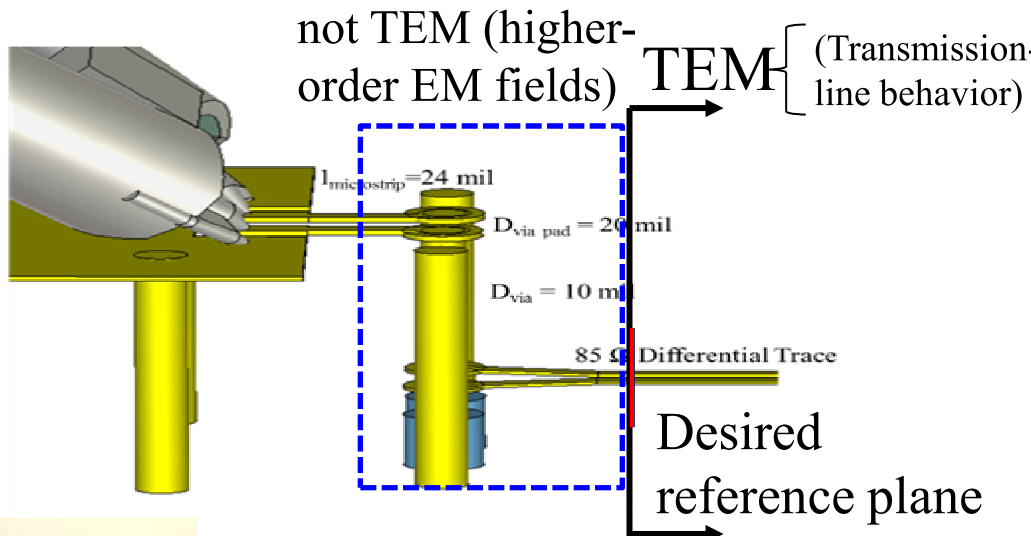
Establishing Best Practices

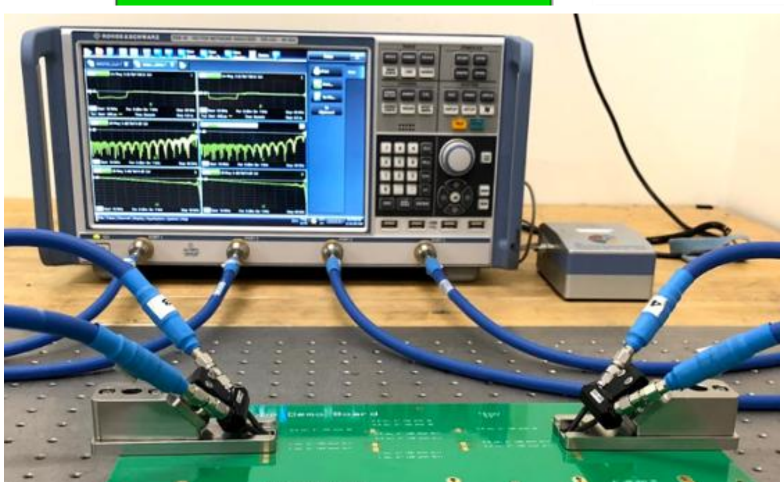
- Straight traces (at 67 GHz shorter traces will be necessary anyway and save space) to avoid resonances from serpentinig
- Universal footprint that ensures good signal return (GND) at the via transition, i.e., well-designed ground return via pattern to avoid coupling to parallel-plate modes
- Via stitching that is randomized around a nominal spacing
- Careful design with full-wave EM simulation to ensure all of the above

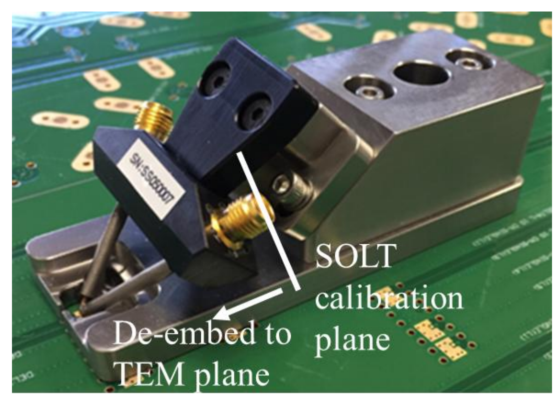
Probing Solution to 67 GHz

- Optimize probe and via transition simultaneously with EM simulation to achieve a RL>6dB at 67 GHZ
- Achieve an IL < 6 dB at 67 GHz by using shorter 2X Thru









PacketMicro D-probe

Conclusion

Achieving a good outcome for Delta-L to 67 GHz will necessitate:

- Excellent design using EM simulation to develop the design
- High-quality S-parameter measurements

Some EM Simulation Tools (incomplete)

- EMCoS Studio (MoM)
- Cadence Clarity (TD-FDTD, FD-FEM)
- CST Studio Suite – Dassault Systems (TD-FIT, FD-FEM)
- HFSS – Ansys (FD-FEM)
- EMA3D (TD-FDTD)

Thank you!

Questions?

(May also send Jim Drewniak questions or request for slides james.drewniak@clearsig.com)